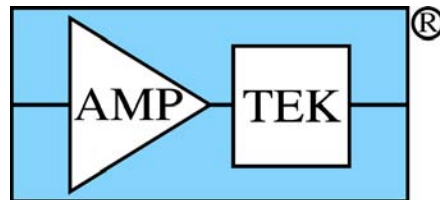


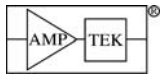
## **X-123SDD**

Complete X-Ray Spectrometer with Silicon Drift Detector (SDD)

User Guide and Operating Instructions

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# 1 INTRODUCTION

## 1.1 DESCRIPTION

The X-123SDD combines in a single package Amptek's high performance X-ray spectroscopy components: (1) the XR-100SDD silicon drift X-ray detector and preamplifier, (2) the DP5 digital pulse processor and MCA, and (3) the PC5 power supply. The result is a complete system which can fit in your hand with no performance compromise. It requires only +5 VDC power and a standard communication interface. With the X-123 anyone can rapidly obtain high quality X-ray spectra.

The X-123SDD uses a silicon drift detector (SDD) similar to a Si-PIN photodiode but with a unique electrode structure to improve energy resolution and increase count rates. The SDD is mounted on a thermoelectric cooler along with the input FET and coupled to a custom charge sensitive preamplifier. The thermoelectric cooler reduces the electronic noise in the detector and preamplifier but the cooling is transparent to the user: it operates like a room temperature system.

The pulse processor is the DP5, a second generation digital pulse processor (DPP) which replaces both the shaping amplifier and MCA found in analog systems. The digital technology improves several key parameters: (1) better performance, specifically better resolution and higher count rates; (2) greater flexibility since more configuration options are available and selected by software, and (3) improved stability and reproducibility. The DPP digitizes the preamplifier output, applies real-time digital processing to the signal, detects the peak amplitude, and bins this in its histogram memory. The spectrum is then transmitted to the user's computer. The PC5 supplies the power to the detector, including low voltages for the preamps, high voltage to bias the detector, and a supply for the thermoelectric cooler which provides closed loop control with a maximum temperature differential of 85 °C. All of these are under software control. The X-123SDD input power is unregulated +5 VDC with a current of about 250 mA.

The complete system is packaged in 7 x 10 x 2.5 cm<sup>3</sup> aluminum box. The detector is mounted on an extender, with lengths from 0 to 9" (vacuum flanges are available). In its standard configuration only two connections are required: power (+5 VDC) and communications (USB, RS232, or Ethernet). An auxiliary connector provides several additional inputs and outputs used if the X-123SDD will be integrated with other equipment. This includes an MCA gate, timing outputs, and eight SCA outputs. The X-123SDD is supplied with data acquisition and control software. It also includes an Application Programming Interface (API) DLL to integrate the unit with custom software. Optional accessories include software for analyzing X-ray spectra, several collimation and mounting options, and X-ray tubes to complete a compact system for X-ray fluorescence.

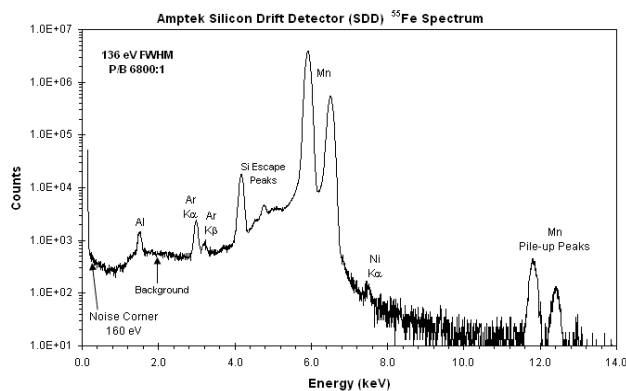


Figure 1-1. Photograph of complete X-123 (left) and a typical <sup>55</sup>Fe spectrum (right).

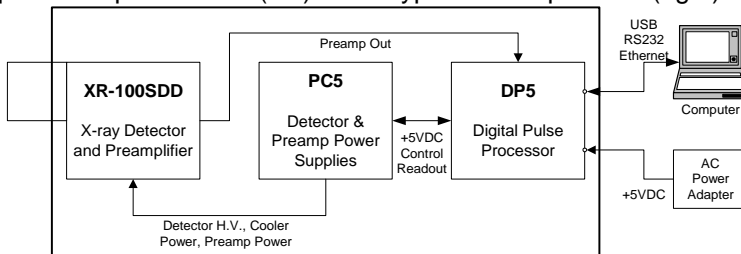
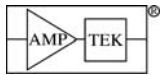


Figure 1-2. Block diagram of the X-123SDD

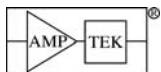


## 2 SPECIFICATIONS

Spectroscopic Performance				
Energy Resolution	135 to 155 eV FWHM @ 5.9 keV			
Electronic Noise (typical)	73 eV FWHM (8.7 e <sup>-</sup> rms)			
Energy Range	Efficiency >25% for X-rays from 1 to 25 keV. May be used outside this range with lower efficiency.			
Peak to Background	7,000 to 1 (ratio of counts from 5.9 keV to 2 keV)			
Maximum Count Rate	Depends on peaking time. Recommended maxima are shown below.			
Peaking Time (μsec)	9.6	4.8	2.4	0.8
Shaping Time (μsec)	4.4	2.2	1.0	0.4
Recommended max input rate (sec <sup>-1</sup> )	4.9x10 <sup>4</sup>	1.0x10 <sup>5</sup>	1.9x10 <sup>5</sup>	5.6x10 <sup>5</sup>
Typical resolution (eV FWHM @ 5.9 keV)	140	150	160	200

Detector and Preamp	
Detector Type	Si drift diode (SDD)
Detector Active Area	7 mm <sup>2</sup> (collimator area 4.45 mm <sup>2</sup> )
Detector Thickness	450 μm
Be Window Thickness	1 mil (25 μm) or 0.5 mil (12.5 μm)
Thermoelectric Cooler	2-stage (85° ΔT <sub>max</sub> )
Preamp Type	Amptek custom reset, charge sensitive
Preamp Conversion Gain	1 mV/keV

Pulse Processor																	
Gain	Combination of coarse and fine gain yields overall gain continuously adjustable from 0.84 to 127.5.																
Coarse Gain	Software selectable from 1.12 to 102 in 16 log steps. <table border="1" style="margin-left: 20px;"> <tr> <td>1.12</td><td>2.49</td><td>3.78</td><td>5.26</td><td>6.56</td><td>8.39</td><td>10.10</td><td>11.31</td> </tr> <tr> <td>14.56</td><td>17.77</td><td>22.42</td><td>30.83</td><td>38.18</td><td>47.47</td><td>66.26</td><td>102.0</td> </tr> </table>	1.12	2.49	3.78	5.26	6.56	8.39	10.10	11.31	14.56	17.77	22.42	30.83	38.18	47.47	66.26	102.0
1.12	2.49	3.78	5.26	6.56	8.39	10.10	11.31										
14.56	17.77	22.42	30.83	38.18	47.47	66.26	102.0										
Fine Gain	Software selectable, 0.75 to 1.25, 10 bit resolution																
Full Scale	1000 mV input pulse @ X1 gain																
Gain Stability	<20 ppm/° C (typical)																
Pulse Shape	Trapezoidal. (A semi-Gaussian amplifier with shaping time τ has a peaking time of 2.2τ and is comparable in performance with the trapezoidal shape of the same peaking time.)																
ADC Clock Rate	20 or 80 MHz, 12 bit ADC																
Peaking Time	30 software selectable peaking times between 0.2 and 102 μs, corresponding to semi-Gaussian shaping times of 0.1 to 45 μs.																
Flat Top	16 software selectable values for each peaking time (depends on the peaking time), > 0.05 μsec.																
Baseline Restoration	Asymmetric, 16 software selectable slew rate settings																
Fast Channel Pulse Pair Resolving Time	120 nsec																

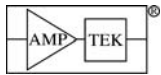


Dead Time Per Pulse	1.05 times the peaking time. No conversion time.
Maximum Count Rate	$4 \times 10^6 \text{ sec}^{-1}$ (periodic). Output count rate of $7 \times 10^5 \text{ sec}^{-1}$ for a random input of $1.9 \times 10^6 \text{ sec}^{-1}$ .
Dead Time Correction	Manual correction based on Fast Channel measurement of ICR. Accurate to 1% for ICR < 1 Mcps under typical conditions.
Pulse Selection Options	Pile-up rejection, risetime discrimination, gate

<b>Multichannel Analyzer</b>	
Number of channels	256, 512, 1024, 2048, 4096, or 8192 channels.
Bytes per channel	3 bytes (24 bits) - 16.7M counts
Acquisition Time	10 msec to 466 days
Data Transfer Time	1k channels in 12 milliseconds (USB) or 280 milliseconds (RS-232)
Conversion Time	None.
Presets	Time, total counts, counts in an ROI, counts in a channel
MCS Timebase	10 millisecc/channel to 300 sec/channel
External MCA Controls	Gate input: Pulses accepted only when gated on by external logic. Input can be active high or active low. Software controlled.
Counters	Slow channel events accepted by MCA, Incoming counts (fast channel counts above threshold), SCA8 counts, event rejected by selection logic, and external event counter. Sixteen ROI counters.

<b>Auxiliary Inputs/Output</b>	
Single Channel Analyzers	8 SCAs, independent software selectable LLDs and ULDs, LVCMOS (3.3V) level (TTL compatible)
Digital Outputs	Two independent outputs, software selectable between 8 settings including INCOMING_COUNT, PILEUP, MCS_TIMEBASE, etc. LVCMOS (3.3V) levels (TTL compatible).
Digital Inputs	Two independent inputs, software selectable for MCA_GATE, EXTERNAL_COUNTER
I/O	Two general purpose I/O lines for custom application
Digital Oscilloscope	Displays oscilloscope traces on the computer. Software selectable to show shaped output, ADC input, etc., to assist in debugging or optimizing configurations.

<b>Communications</b>
USB 2.0 full speed (12 Mbps)
RS-232 at 115.2k or 57.6k baud
Ethernet (10base-T) (future release)



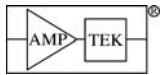
<b>Power</b>	
Nominal Input:	+5 VDC at 500 mA (2.5 W) (typical). Current depends strongly on detector $\Delta T$ . Ranges from 300 to 800 mA at 5 VDC.
Input Range:	4 V to 5.5 V (at 0.4 to 0.7 A typical)
Initial transient:	2 A for <100 $\mu$ sec
High Voltage Supply	Internal multiplier, software control 100-1500V (260V typ), negative polarity
Cooler Supply:	Closed loop controller with $\Delta T_{max} = 85$ °C

<b>Physical</b>	
Dimensions	7 x 10 x 2.5 cm (2.7 x 3.9 x 1 in) excluding extender
Extender Lengths	1.5" (3.8 cm) standard. Options include 3/8", 5", 9", and vacuum flanges.
Weight	180 g (6.3 oz)

<b>General and Environmental</b>	
Operating temperature	-20°C to +50°C
Warranty Period	1 Year
Typical Device Lifetime	5 to 10 years, depending on use
Storage and Shipping	Long term storage: 10+ years in dry environment Typical Storage and Shipping: -20°C to +50°C, 10 to 90% humidity non condensing
Compliance	RoHS Compliant

*Customization*

Amptek, Inc. provides many tailored configurations on an OEM basis and has designed the X-123SDD to be easily tailored and customized. The DP5 digital pulse processor inside the X-123SDD can be customized to support various applications. Please contact Amptek, Inc for more details.



### 3 CAUTIONS AND WARNINGS



1) HIGH VOLTAGES ARE PRESENT IN THE X-123SDD. They are internal to the package so do not represent a safety hazard if the unit remains enclosed.



2) THE DETECTOR CONTAINS A THIN, FRAGILE BE WINDOW. If this window is damaged, the detector will be destroyed and cannot be repaired. Be windows damaged due to improper handling are not covered under warranty.

3) DO NOT DROP OR CAUSE MECHANICAL SHOCK TO THE X-123SDD. Components inside the detector are mechanically fragile and may be damaged if the unit is dropped.

4) DO NOT REMOVE the red protective cap from the detector until data is to be taken. The detector window is made from thin beryllium (0.001 in / 25  $\mu$ m thick) which is extremely brittle and can shatter very easily. Do not have any object come in contact with the window. Do not touch the window because the oil from the fingers will cause it to oxidize. The window cannot be repaired. If the window is damaged the detector assembly must be replaced. Be windows damaged due to improper handling will not be covered under warranty. Keep the red protective cover nearby at all times and cover the detector when the instrument is not in use.

**BERYLLIUM WINDOWS DAMAGED BY IMPROPER HANDLING WILL NOT BE COVERED BY THE WARRANTY.**

5) RADIATION DAMAGE to the detector will occur if it is exposed to a high flux environment. Synchrotron Radiation Beams should be modified with attenuators before they are allowed to strike the detector or the fluorescence target. Damage to the detector will be permanent if the flux from an X-Ray Tube, a strong nuclear radiation source, or an accelerator is not attenuated.

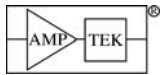
**A RADIATION DAMAGED DETECTOR WILL NOT BE COVERED UNDER WARRANTY.**

6) No operator serviceable parts inside. Refer servicing to Amptek, Inc. To prevent electrical shock, do not remove covers.

7) For the latest information about this analyzer, including firmware upgrades, application software upgrades, application information, and product information, go to: <http://www.amptek.com>.

#### Warranty

AMPTEK, INC. warrants to the original purchaser this instrument to be free from defects in materials and workmanship for a period of one year from shipment. AMPTEK, INC. will, without charge, repair or replace (at its option) a defective instrument upon return to the factory. This warranty does not apply in the event of misuse or abuse of the instrument or unauthorized alterations or repair. AMPTEK, INC. shall not be liable for any consequential damages, including without limitation, damages resulting from the loss of use due to failure of this instrument. All products returned under the warranty must be shipped prepaid to the factory with documentation describing the problem and the circumstances under which it was observed. The factory MUST be notified prior to return shipment. The instrument will be evaluated, repaired or replaced, and promptly returned if the warranty claims are substantiated. A nominal fee will be charged for unsubstantiated claims. Please include the model and serial number in all correspondence with the factory.



## 4 GETTING STARTED



- High voltages are present in the X-123SDD. They are internal to the package so do not represent a safety hazard if the unit remains enclosed.



- The detector contains a thin, fragile Be window. If this window is damaged, the detector will be destroyed and cannot be repaired. Do not touch the window!
- The components inside the detector hybrid are mechanically fragile and may be damaged if the unit is dropped.

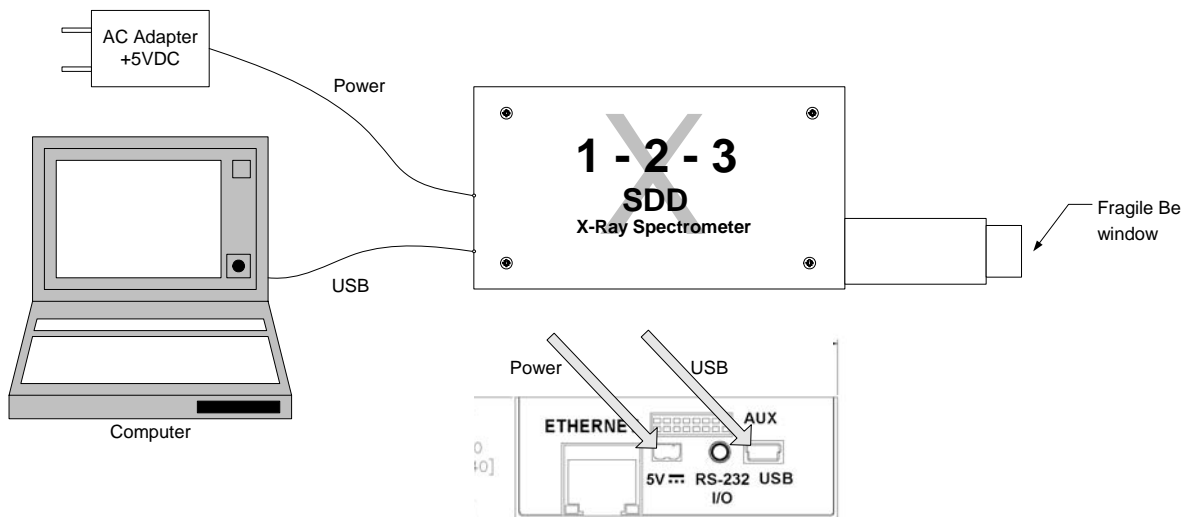
### 4.1 EQUIPMENT LIST

- X-123SDD X-Ray Spectrometer.
- Mini USB cable.
- +5 VDC power supply.
- Amptek Installation CD.
- A PC (supplied by the user) with Windows 98SE or higher (Windows XP PRO SP2 recommended).

### 4.2 MAKING CONNECTIONS

- 1) Plug the USB cable into the X-123SDD mini-USB connector (on the back panel) and the PC.
- 2) Plug the DC power supply into a 110/220 AC outlet. Connect the other end to the X-123SDD power supply input, which is labeled “5VDC” and is located on the back panel. The X-123SDD powers up whenever it is plugged in.

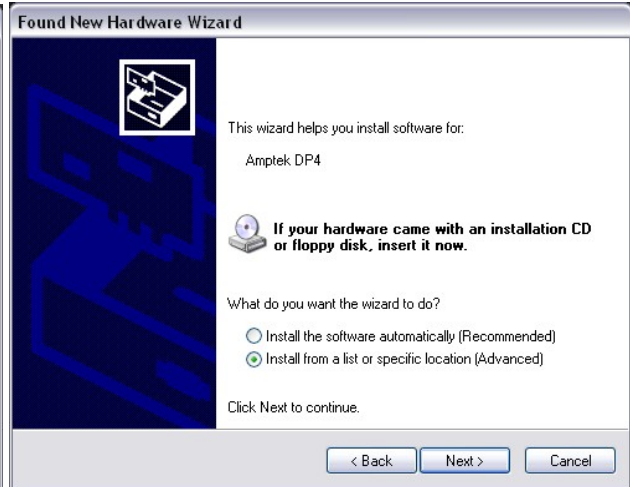
NOTE: Grounding is critical to obtaining the best performance. Amptek strongly recommends using a single point ground for the system. To ensure this use a 3-prong to 2-prong adapter on the power supply of any notebook computer. This prevents the notebook from introducing a second ground into the system.



### 4.3 INSTALL SOFTWARE

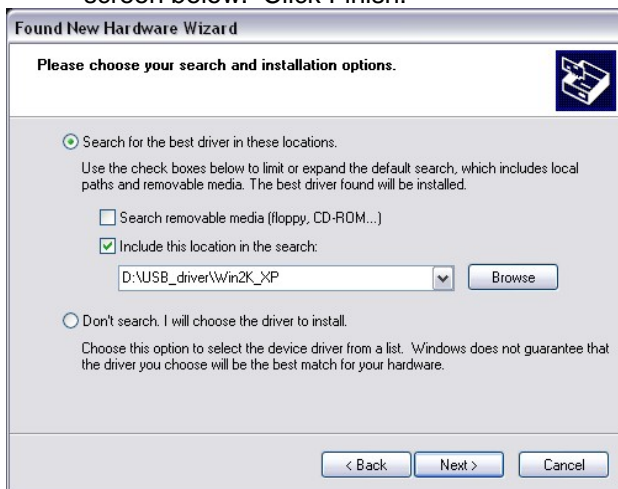
- 1) Turn on the PC and make sure you are logged in as an administrator.
- 2) The “Found New Hardware Wizard” should automatically appear when the X-123SDD is connected and powered on for the first time.
- 3) Select “No, not this time” and click “Next>”.
- 4) Select “Install from a list or specific location (Advanced)” and click Next>.





5) Select “Search for the best driver in these locations.” Then check the box “Include this location in the search.” Select “Browse” and navigate to the \USB\_driver\Win2K\_XP folder of the Amptek Installation CD. Click Next>.

6) Once the driver has been installed you will see the “Completing the Found New Hardware Wizard” screen below. Click Finish.

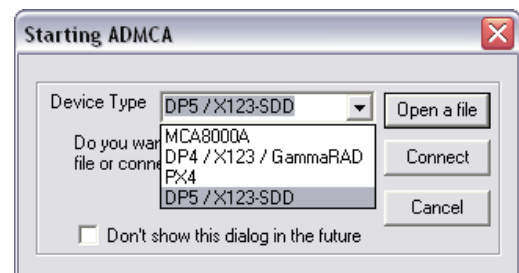


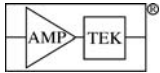
7) Now that the USB driver is installed, browse to the Amptek Installation CD and copy the ADMCA directory to the local computer’s C:\ drive. For example if the computer’s CD drive is the letter D, copy D:\ADMCA to C:\ADMCA. **The software will not run from CD, it must be copied to the local drive.**

8) Browse to the C:\ADMCA directory and open the Admca.exe file to launch the software. Right click on the Admca.exe file and select Create Shortcut. This shortcut can then be dragged to the desktop.

#### 4.4 CONFIGURING THE UNIT

- 1) Launch the ADMCA software.
- 2) When the “Starting ADMCA” box appears as to the right, select DP5 / X-123SDD and click on “Connect.” The X-123SDD unit should now be connected to the software. To verify this, confirm that a serial number for the DP5 is shown in the top right corner of the software and that the USB symbol located at the bottom right corner of the software is green.

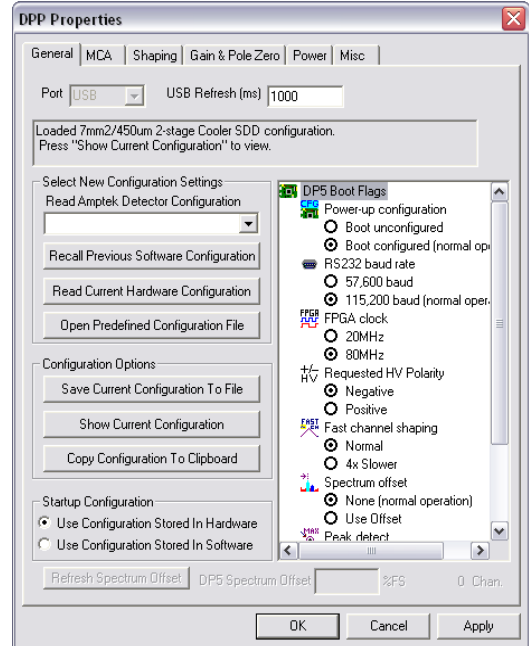




- 3) Now that the X-123SDD is connected, the proper configuration must be selected for the detector. The ADMCA software includes configurations for most Amptek detectors. These configurations are identified by the detector material, dimensions, and cooler type.

NOTE: The X-123SDD remembers the last configuration, so when powering the system for the first time and clicking Connect, the factory configuration is displayed on test sheet shipped with the detector.

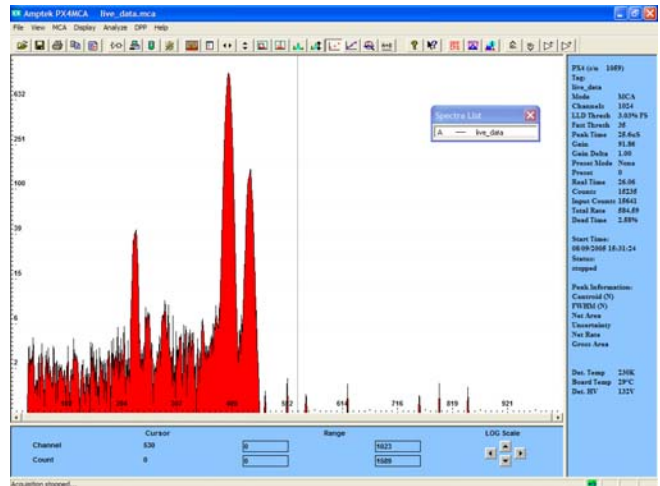
- 4) To select a configuration, select "DPP Setup" under the "DPP" dropdown list in the software or by clicking the "acquisition setup" button on the toolbar. The dialog box shown in the figure will appear. The configurations can be selected through the dropdown menu labeled "Read Amptek Detector Configuration."
- 5) Once the correct configuration is selected from the dropdown menu the indented grey area above the dropdown menu should read (for example) "Loaded SDD 7mm2/450um 2-Stage Cooler configuration." Click "Show Current Configuration" to view the settings. A box will appear with the settings. Click OK to exit the box.

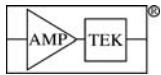


- 6) To apply the selected configuration click the "Apply" button. Then select the "OK" button to exit this dialog box. The default configuration for this detector has now been loaded. To tailor the configuration, select the "acquisition setup" toolbar button.

**4.5 MAKING A MEASUREMENT**

- 1) Now that the X-123SDD has the appropriate configuration, an acquisition can be started. Place a source in front of the detector. To start an acquisition, press the space bar. The space bar will also stop an acquisition. It may take the detector a few minutes to stabilize, so if the acquisition does not look correct wait a few minutes and then press the "A" key on the keyboard to clear the acquisition and begin a new one. It can take up to 2 minutes for an Amptek detector to stabilize after a configuration has been sent.
- 2) Once the detector has stabilized adjust some of the thresholds which prevent low-end noise and other unwanted counts from affecting the spectrum. This can be done automatically by the software by clicking the "Tune Slow/Fast" button on the toolbar. This must be done with no source in front of the detector.
- 3) A common adjustment is to change the gain of the X-123SDD. Increasing the gain reduces the full scale energy range and reducing the gain increases the full scale energy range (e.g. gain of x100 = 8 keV, gain of x50 = 16 keV). This can be done in the "Gain & Pole Zero" tab of the DPP properties dialog box or by using the gain buttons on the toolbar. It is necessary to readjust the thresholds whenever the gain is changed. This can be done automatically as explained in the previous step.
- 4) The "Help" menu explains the features of the software.





## 4.6 NOTES

### 4.6.1 Regions of Interest (ROI)

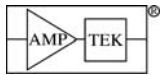
To mark an ROI, click the “Edit ROI” button on the toolbar. The cursor will change to a vertical arrow. Click and hold the left mouse button at the left base of the peak you want to mark and drag the cursor across the peak. You will see the color change as the ROI is marked. Release the mouse button at the right end of the peak. If you click the mouse into the highlighted region, it will become a lighter color indicating that it is the selected ROI. The Peak Information on the right hand info panel is displayed for the selected ROI.

### 4.6.2 Calibrating the Horizontal Axis

The horizontal (x) axis in the plot window defaults to channels. To calibrate the scale to e.g. energy, you must know the energy of at least two peaks in your spectrum. First mark two regions of interest as described above. Then click on the Calibrate button on the toolbar. Click the cursor into the first ROI in the plot window (it becomes highlighted), and then click Centroid in the Calibrate box. This takes the centroid of the peak and puts it as the channel value of the first point that will be used for the calibration. Enter in the value of that centroid, e.g. the energy of that peak, into the Value box. Now click Add. The first point will appear in the list. Repeat for the second peak you highlighted. There should now be two lines in the list. Enter in the appropriate units in the “Units” box, e.g. “Energy (keV)” and then click OK. The horizontal scale will now be displayed in the calibrated units. To toggle between calibrated and non-calibrated units, press F7 on the keyboard.

## 4.7 TROUBLESHOOTING

- By default, the software accumulates the counts (MCA mode). During set-up it may be convenient to use “DELTA” mode, where counts are not integrated but are updated every second (i.e. only one second’s worth of data are displayed every second). Click the toolbar icon marked “MCA/DELTA Mode” to toggle between DELTA and MCA mode.
- If no spectrum appears, check that the system is acquiring data. The “Status” on the right hand Info Panel should read “acquiring.”
- Sometimes no spectrum will appear if PUR is enabled and the Fast Threshold is set improperly (in the DPP Properties-Shaping tab). Turn PUR off and check if the spectrum appears. If it does then the Fast Threshold needs to be set correctly. Remove any source from in front of the detector and click the “Tune Fast Threshold” button. Put the source back and check if the spectrum appears. If it does not then you will have to adjust it manually as described below.
- The Fast and Slow Thresholds can be adjusted manually. First turn off PUR as described above. Then click the cursor to channel 1 and press F8. This will set the Slow Threshold (LLD) to channel 1. This will show the noise of the system. Click the cursor just to the right of the noise and then press F8. Press the “A” key to clear. There should be no counts accumulating. Now put the device into “Delta” mode by clicking the Delta button on the toolbar. Open the DPP Properties and go to the Shaping page. Adjust the Fast Threshold until 5 to 15 counts per second appear in the Input Counts in the right-hand Info Panel. Now turn on PUR and click OK. Click the Delta button to get back to normal MCA mode and put the source back in front of the detector. The Input Counts should slightly exceed the Counts at low count rate.
- If problems persist there may be a communication or configuration problem. Unplug the X-123SDD power and close the software. Then open the software and plug in the X-123SDD power adapter. In the bottom left-hand corner of the software you should see a “1 Detected” for the USB connection. Once you see this, click on Connect. Then go to the DPP Properties page and reload the appropriate default configuration as discussed above and try the acquisition again.
- Grounding is critical to obtaining the best performance. Amptek strongly recommends using a single point ground for the system. We have observed several laptops in which the charger introduced ground noise. In these cases, better performance was found by (1) using a 3-prong to 2-prong adapter on the power supply of any notebook computer and (2) making a separate ground connection from the chassis of the X-123SDD. Note that the AC/DC supply is isolated.



## 5 ELECTRICAL INTERFACES

### 5.1 ELECTRICAL SPECIFICATIONS

#### 5.1.1 Absolute Maximum Ratings

Operating Temperature -20°C to +50°C

All parts in the X-123SDD are rated to the industrial temperature range, -40 to +85°C.

Power Supply Voltage +6.0 VDC

NOTICE: Stresses above those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only. Performance at these levels is not implied. Exposure to the conditions of the maximum ratings for an extended period may degrade device reliability.

#### 5.1.2 DC Characteristic

Characteristic	Symbol	Min	Typ	Max	Units	Conditions
<b>Power Supply</b>						
Supply Voltage	$V_{IN}$	4.0	5.0	5.5	V	
Supply Current	$I_{IN}$			0.9	A	$V_{IN} = 5.0V$ , initial cool down
			0.70	A	$V_{IN} = 5.0V$ , steady state full cooling	
			0.40	A	$V_{IN} = 5.0V$ , $\Delta T=70^{\circ}C$	
			0.35	A	$V_{IN} = 5.5V$ , $\Delta T=70^{\circ}C$	
			0.50	A	$V_{IN} = 4.0V$ , $\Delta T=70^{\circ}C$	
			0.30	A	$V_{IN} = 5.0V$ , no cooling or bias	
Inrush Current	$I_{INRUSH}$		2		A	<100 $\mu$ sec
Input Capacitance	$C_{IN}$		50		$\mu$ F	

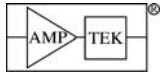
- Supply current data measured at room temperature (20°C).
- Total supply current depends very strongly on the set point for the thermoelectric cooler and on the ambient temperature. The cooler draws up to 2/3 of the total power.

#### USB

- The USB interface follows the USB 2.0 Full Speed (12 MBPS) specifications. No separate table is included here. See the DP5 User manual for more information.

RS-232	Symbol	Min	Typ	Max	Units	Conditions
RX input range		-25		+25	V	
RX threshold low		0.6	1.2		V	
RX threshold high			1.5	2.4	V	
RX hysteresis			0.5		V	
RX input resistance		3	5	7	K $\Omega$	
TX voltage swing		+/- 5	+/- 5.4		V	3 K $\Omega$ to ground
TX output resistance		300	10 M		$\Omega$	Unpowered
TX short-circuit current				+/- 60	mA	
baud rate		57.6		115.2	Kbaud	
baud rate accuracy				$\pm 1.5\%$		

- The RS232 interface uses only RXD/TXD lines (no hand-shaking).
- The transceiver is a MAX3227. Please refer to the MAXIM data sheet for further specifications.

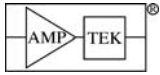


<b>AUX OUT</b>						
Output High Voltage	$V_{OH}$	3.0 1.8	3.3		V V	Typ: No load Min: $I_{OH} = -100 \mu A$ Min: $I_{OH} = -16 mA$
Output Low Voltage	$V_{OL}$		0.0	0.1 1.2	V	Typ: No load Min: $I_{OH} = 100 \mu A$ Min: $I_{OH} = 16 mA$
Output Resistance	$R_{OUT}$		50		$\Omega$	
<b>AUX IN</b>						
Input Voltage		0		5.5	V	
Positive-going Input Threshold	$V_{T+}$	1.4		2.35	V	
Negative-going Input Threshold	$V_{T-}$	0.7		1.45	V	
Input Resistance	$R_{IN}$		100		$K\Omega$	
<b>SCA OUT</b>						
Output High Voltage	$V_{OH}$	2.9 2.0	3.3		V V	Typ: No load Min: $I_{OH} = -100 \mu A$ Min: $I_{OH} = -12 mA$
Output Low Voltage	$V_{OL}$		0.0	0.2 1.0	V	Typ: No load Max: $I_{OH} = 100 \mu A$ Max: $I_{OH} = 12 mA$
Output Resistance	$R_{OUT}$		47		$\Omega$	
<b>I/O</b>						
Output High Voltage	$V_{OH}$		3.3		V	
Output Low Voltage	$V_{OL}$		0		V	
	$I_{OH}$	30		300	$\mu A$	$V_{OH} = GND$
	$I_{OL}$	10	25		$mA$	$V_{OL} = 1V$

- The AUX OUT lines are the output of a 74LVC2G14 ( $V_{dd}=3.3V$ ) with 50  $\Omega$  series resistance.
- The AUX IN lines are input to a 74LVC2G14 ( $V_{dd}=3.3V$ ) with 100  $k\Omega$  to ground.
- The I/O lines are connected to a MAX7328 ( $V_{dd}=3.3V$ ), which are open-drain with a weak pull-up.

**5.2 COMMUNICATION**

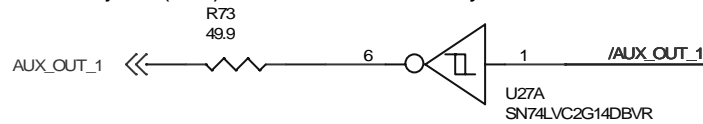
Please refer to the DP5 User Manual and the DP5 Programmer's Guide.



### 5.3 AUXILIARY INPUT AND OUTPUTS

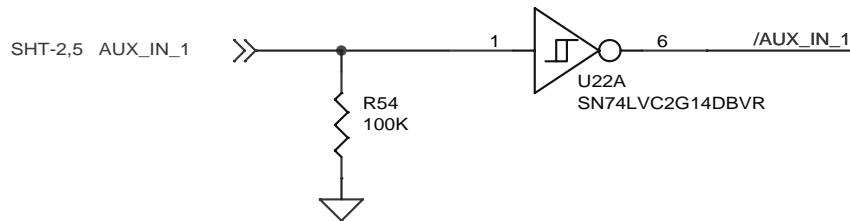
#### AUX\_OUT\_1 and \_2

- Each of these two lines can be configured, via software, to output any one of several logic signals in the FPGA. These logic signals are associated with pulses processed by the FPGA.
- The pulse timing and duration depends on which output is commanded.
- AUX\_OUT\_1 is connected to the Interconnect (J5), to the auxiliary connector (J6), and can be jumpered to the stereo jack (J10). AUX\_OUT\_2 is only connected to the auxiliary connector (J6).



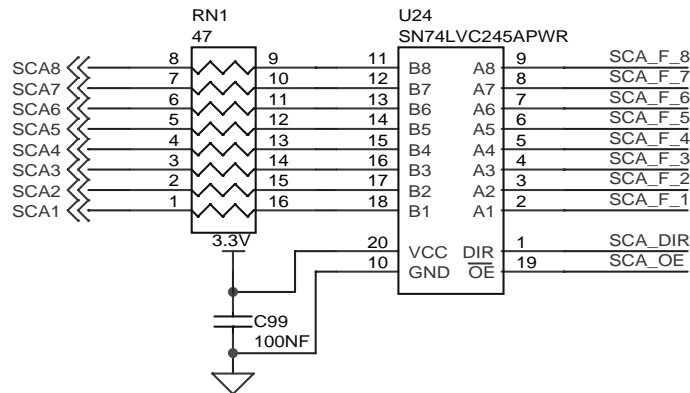
#### AUX\_IN\_1 and \_2

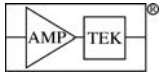
- Each of these two lines can be configured, via software, to input any one of several logic signals in the FPGA. These logic signals are associated with pulses processed by the FPGA.
- AUX\_IN\_1 is connected to the Interconnect (J5), to the auxiliary connector (J6), and can be jumpered to the stereo jack (J10). AUX\_IN\_2 is only connected to the auxiliary connector (J6).



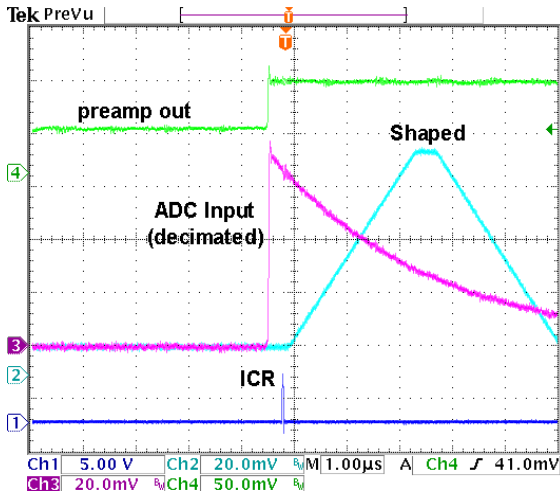
#### Single Channel Analyzers (SCAs)

- Each of the eight SCAs has an independently assignable LLD and a ULD. If the shaped pulse peaks with the range of an SCA, between its LLD and ULD, then a logic signal is output.
- These output pulses are 100 nsec wide (the ability to select longer pulse widths is a future enhancement.)

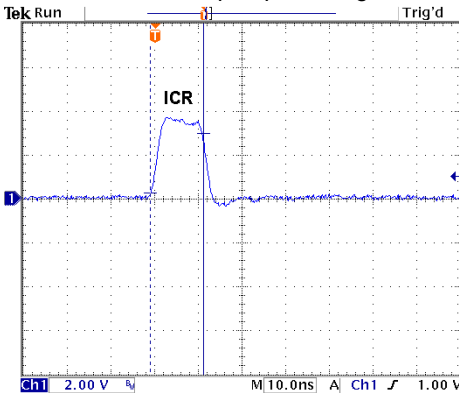




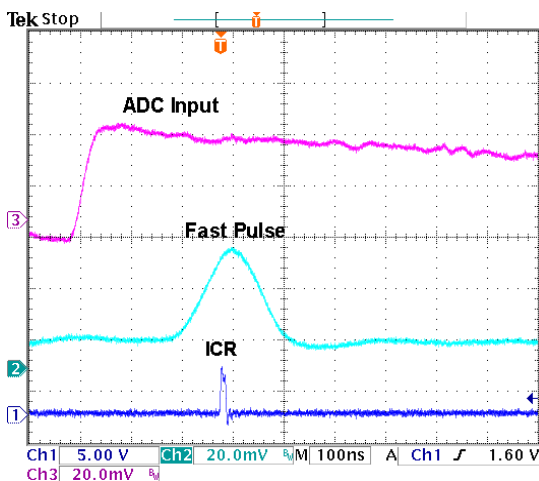
### 5.4 TIMING OF AUXILIARY INPUTS AND OUTPUTS



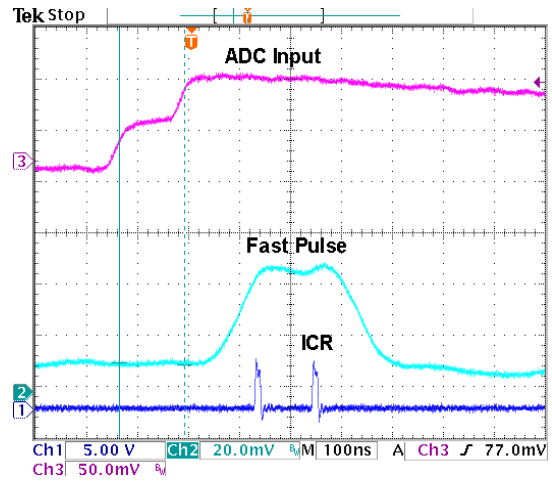
Preamp output, ADC input, shaped pulse ( $T_{peak}$  of 2.4  $\mu$ sec and  $T_{flat}$  of 0.8  $\mu$ sec) and ICR (logic pulse indicating that a fast channel pulse occurred). Note that (1) the shaped pulse begins to rise after actual event (due to delays in the digital pipeline), and (2) ICR occurs when the shaped pulse begins to rise.



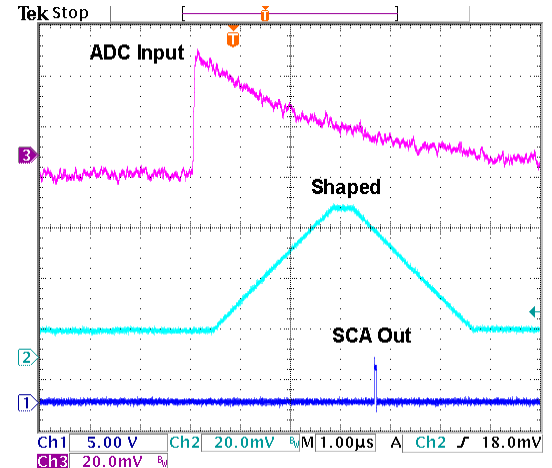
ICR – Measured by scope probe, 10 M $\Omega$ , 15 pF, and 300 MHz scope. One clock (12.5 nsec) wide.



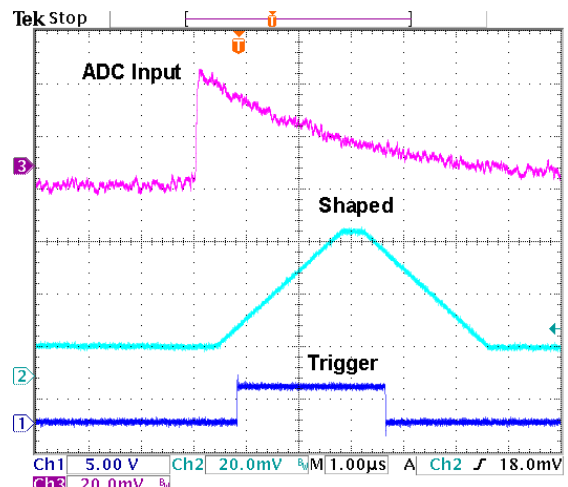
ADC input, fast channel pulse ( $T_{peak}$  of 0.1  $\mu$ sec) and ICR. Similar to plot at left but at high time resolution.



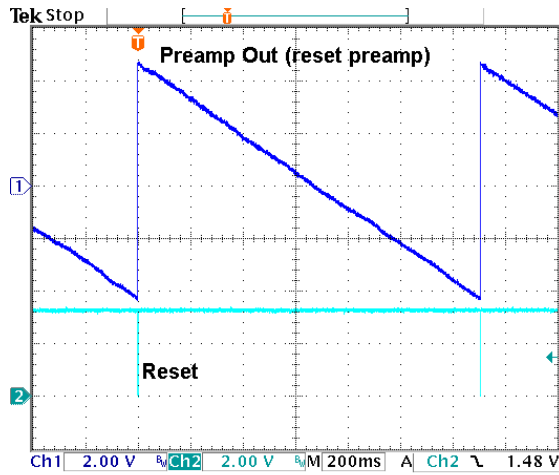
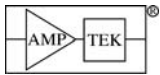
ADC input, fast channel pulse, and ICR. Similar to plot above but shows ability of fast channel to identify pulses separated by 120 nsec.



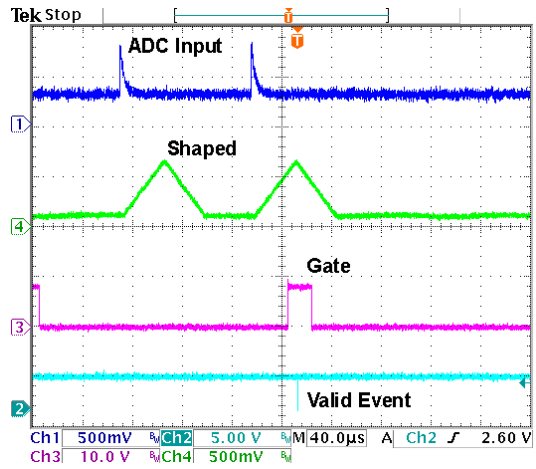
SCA output. Occurs just after the shaped pulse has begun to fall.



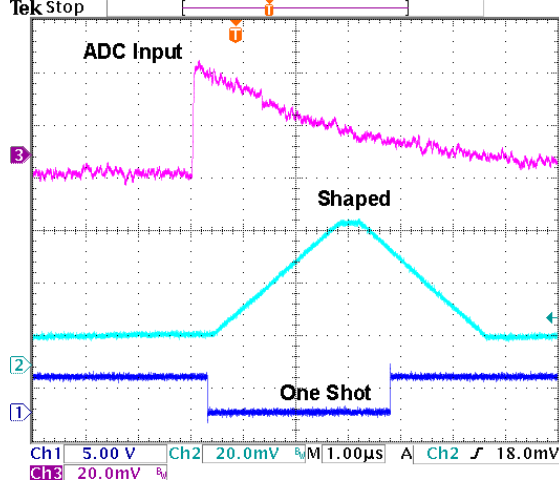
Trigger. Shows when the DPP is looking for the peak of a pulse. Falling edge indicates a peak has been found.



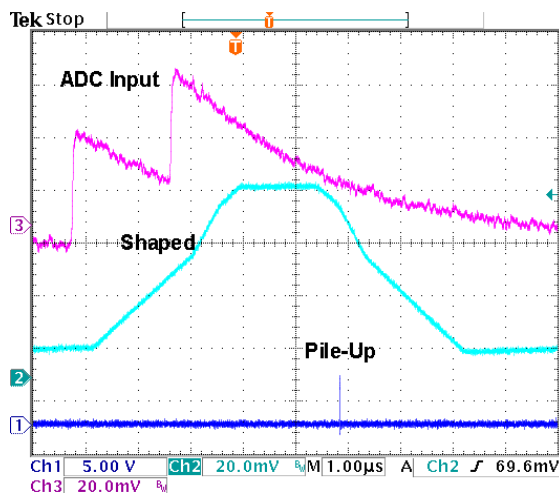
**Detector Reset.** Shows when the DPP detected a reset signal in the preamplifier. The lockout period is the width of the reset signal.



**Gate.** This is an INPUT by which external logic can select pulses to be accepted into the spectrum. If GATE is TRUE at the time the peak is detected (the falling edge of trigger), the event is accepted. In this figure, the second pulse is accepted, not the first.

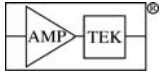


**One-Shot.** Shows when the DPP is looking for possible pile-up. Triggered by the fast channel.



**Pile-Up.** Shows when pile-up was detected. Generated at the end of the final event's one-shot signal.





### 5.5 POWER INTERFACE

Figure 5-1 is a schematic illustrating the circuit at the power input. The PWR\_IN line goes through a Polyfuse and a Schottky diode, then to different switching power supplies in parallel. Five of these are located on the DP5, five on the PC5. Each has a 4.7  $\mu$ F input capacitor. Some turn on as soon as power is applied, while others are under control of the microprocessor.

- Reverse polarity protection: The Polyfuse and diode together protect against reverse input polarity.
- Grounding: The chassis ground of the X-123SDD, which is tied to the box and to the other boards, is connected to the return current pins in J9.

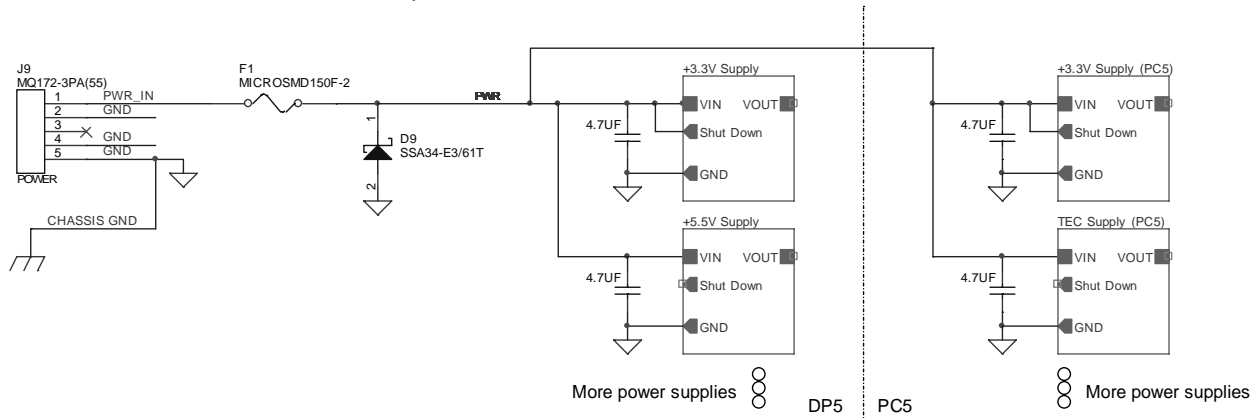


Figure 5-1. Simplified schematic of power supply architecture.

#### Turn-On Transients

Figure 5-2 illustrates the transient currents seen as the X-123SDD turns on. There is a complicated structure, which can be understood from Figure 5-1.

- 1) When 5 VDC is first applied to J9, a large transient current is drawn to charge up the 50  $\mu$ F of input capacitance, from the input capacitors on all the supplies.
- 2) About 400  $\mu$ sec later, the low voltage switching supplies turn on. The maximum inrush current is about 2A, with a duration of <100  $\mu$ sec. It is important that the external supply be able to provide this current. If this current is limited, some of the supplies can be destroyed.
- 3) After the DP5 is powered up, it then powers up the PC5, based on configuration settings stored in the DP5. Depending on the Boot Configuration State "boot flag", this either happens automatically (approx. 2 seconds after power is applied), or upon command from the host PC. The unit draws about 300 mA at 5V.
- 4) When the cooling is turned on,  $I_{IN}$  goes to its maximum, drawing approximately 700 mA.
- 5) In Figure 5-2, the set point was 230K, the ambient 295K, and a SDD on a two stage cooler was used. After about 50 seconds, the temperature approached the set point and so began regulating. The current decreased to its steady state value, 400 mA.

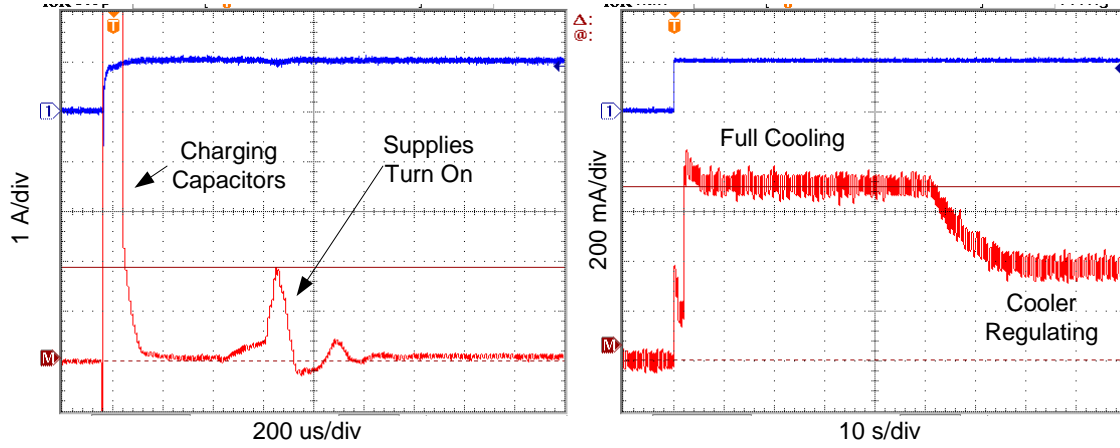
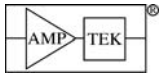


Figure 5-2. Turn-on transients in the X-123SDD.



## 6 MECHANICAL INTERFACE

### 6.1 DIMENSIONS

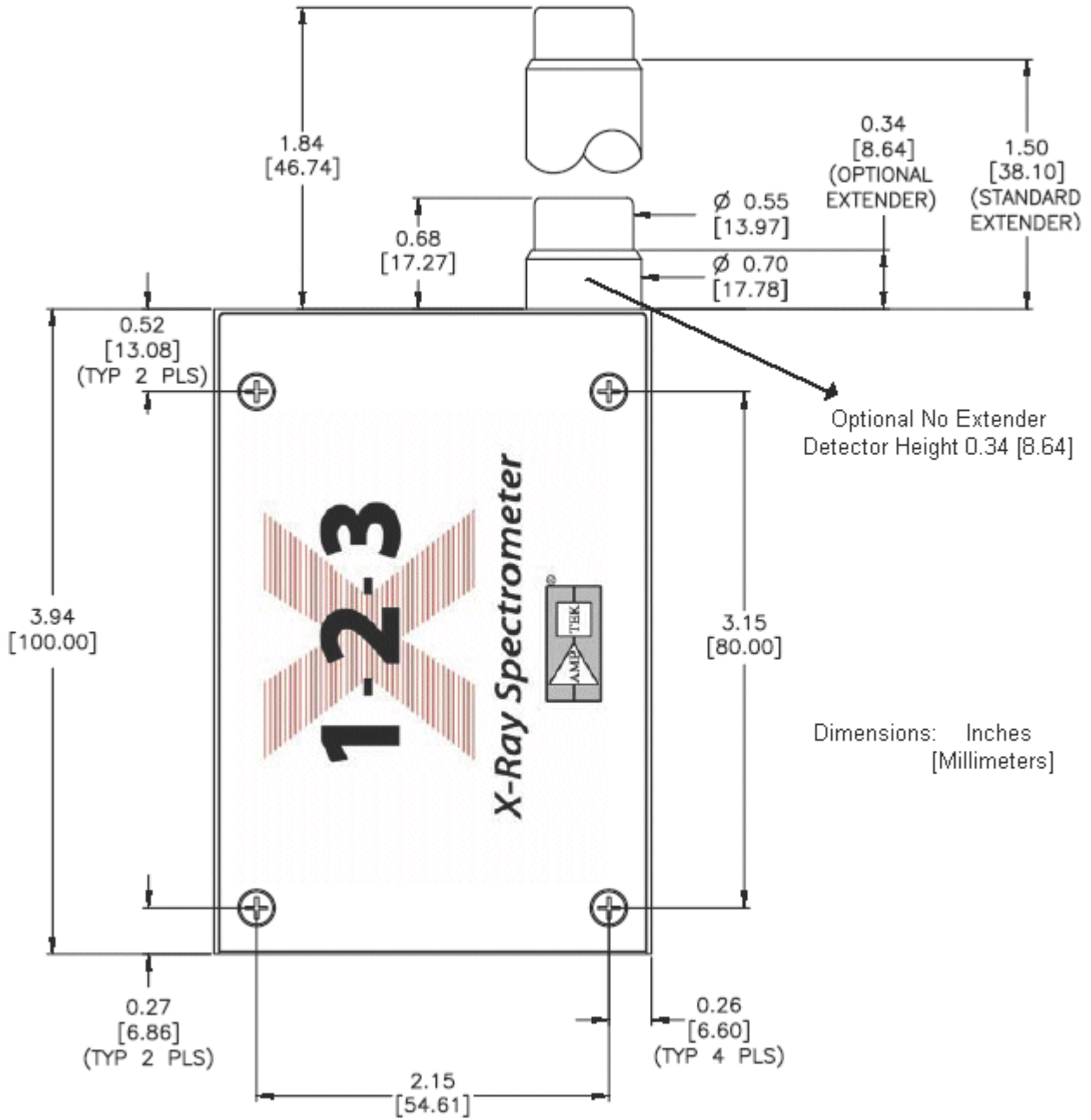


Figure 6-1. Top view of the X-123SDD.

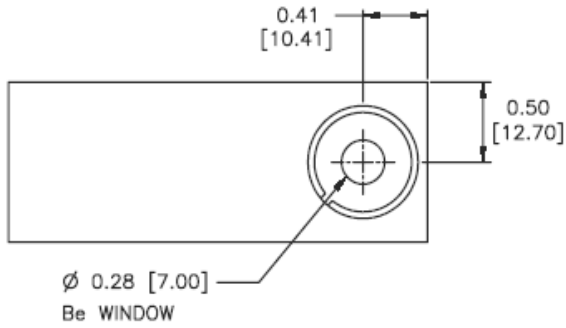
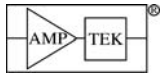


Figure 6-2. Front view of the X-123SDD.

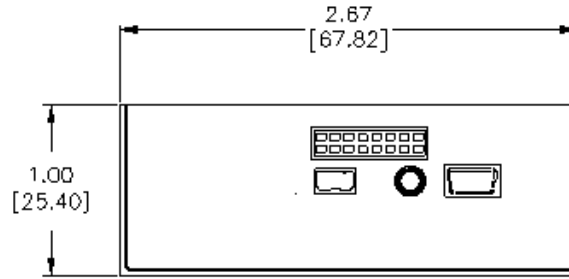


Figure 6-3. Rear view of the X-123SDD.

## 6.2 MOUNTING HARDWARE

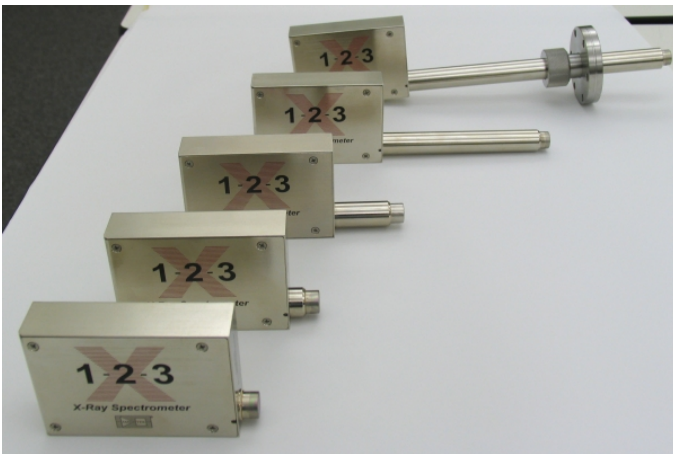
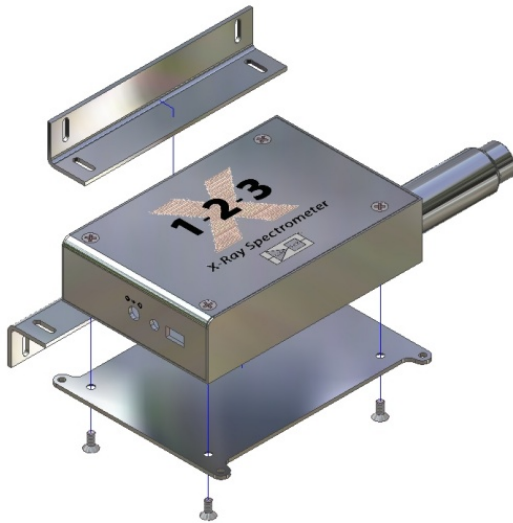


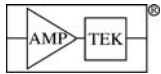
Figure 6-4. Left: Drawing showing how the mounting hardware attaches to the X-123SDD. Right: Photograph of different extender options available with the X-123SDD. The unit at the top has a vacuum flange.

## 6.3 CONNECTORS

### Power

Power Jack on X-123SDD: Hirose MQ172- 3PA(55).

Mating Plug: MQ172-3SA-CV



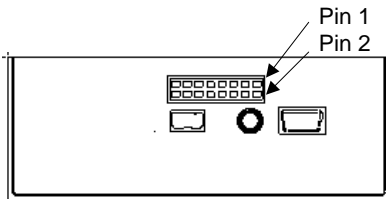
Pin #	Name
1	VIN
2	GND
3	Do Not Connect

*Auxiliary*

2x8 16-pin 2 mm spacing (Samtec part number ASP-135096-01).

Mates with cable assembly (Samtec P/N TCSD-08-S(D)-xx.xx-01-F-N.

Top row odd pins, bottom row even pins.



Pin #	Name	Pin #	Name
1	SCA1	2	SCA2
3	SCA3	4	SCA4
5	SCA5	6	SCA6
7	SCA7	8	SCA8
9	AUX_IN_1	10	AUX_OUT_1
11	AUX_IN_2	12	AUX_OUT_2
13	IO2	14	IO3
15	GND	16	GND

*Ethernet*

Standard Ethernet connector (RJ-45) (available summer '09)

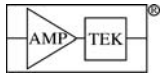
*USB*

Standard USB 'mini-B' jack. (The X-123SDD does not draw power from the USB.)

*RS-232*

Standard 2.5 mm stereo audio jack.

Contact	Signal
Tip	TXD (from DP5)
Ring	RXD (to DP5)
Sleeve	GND



## 7 SOFTWARE INTERFACE

### 7.1 INTERFACE SOFTWARE

#### ADMCA Software

The DP5 can be controlled by the Amptek ADMCA display and acquisition software. This software completely controls and configures the DP5, and downloads and displays the data. It and supports regions of interest (ROI), calibrations, peak searching, and so on. The ADMCA software includes a seamless interface to the XRF-FP quantitative X-ray analysis software package. Runs under Windows 98SE or later on PC compatible computers. Windows XP PRO SP2 or later recommended.

#### DPP API

The DP5 comes with an Application Programming Interface (API) in the form of a DLL library. The user can use this library to easily write custom code to control the DP5 for custom applications or to interface it to a larger system. Examples are provided in VB, VC++, etc. on how to use the API.

#### VB Demonstration Software

The VB demonstration software runs on a personal computer and permits the user to set the DP5 parameters, to start and stop data acquisition, and to save data files. It is provided with source code and can be modified by the user. This software is intended as an example of how to manually control the DP5 through either the USB or RS-232 interface using the most basic calls without the DPP API.

### 7.2 EMBEDDED SOFTWARE

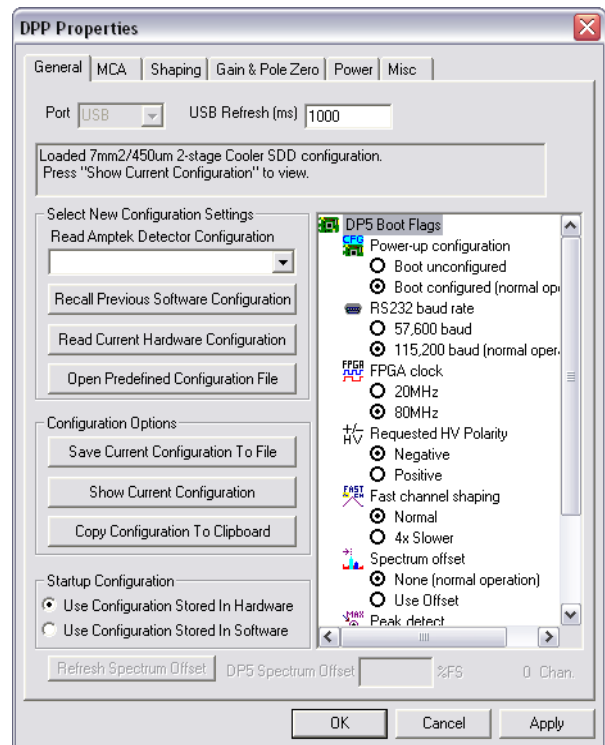
The embedded software is responsible for controlling the pulse processing, controlling the MCA, carrying out some data processing, and interfacing with the personal computer. Firmware updates will be released by Amptek and can be uploaded in the field by the user.

### 7.3 BOOT FLAGS

There are certain parameters that are not contained in the configuration of the unit. These parameters are called boot flags and are stored in the hardware.

#### Boot Configuration State

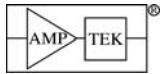
- Boot unconfigured: In this mode, upon power-up, the DP5 will be in an unconfigured state. If present, the PC5 and detector will not be powered on until the first configuration packet is received. Also, the shaper, MCA, etc. are not configured. [After power-up, the status packet byte 23, bit D1 indicates whether the device is configured or unconfigured.]
- Use Nonvolatile Configuration: Upon power-up, the DP5 will use the last configuration it received before it was powered off. It will turn on all supplies, including the PC5 HV & TEC supplies (if present, and if these were previously configured to be powered on). [The HV & TEC supplies will be turned on approximately 2 seconds after power is applied.] The DP5 will be ready to take data, once the detector has cooled.



Note: This setting requires the DP5 to be power-cycled to take effect.

#### RS232 Baud Rate

- 57,600: This primarily exists for backward compatibility with DP4/PX4 RS232 applications.



- 115,200: Recommended, for higher-speed transfers.

Note: This setting requires the DP5 to be power-cycled to take effect.

#### *FPGA Clock*

- 20MHz: Operating the DP5 at 20MHz consumes less power than 80MHz and allows longer peaking times (up to 102us), but limits throughput, minimum peaking time (0.8us), etc.
- 80MHz: This is the recommended clock rate for SDD detectors; it allows faster peaking times (min 0.2us) and higher throughput than 20MHz, but requires a bit more power.

Note: This setting is 'live' and will take effect immediately.

#### *HV Polarity*

The polarity of the HV supply on the PC5 is not under software control; it is configured in hardware, via jumpers set at the factory. This software configuration setting tells the DP5 what polarity is required, and the DP5 will not allow the PC5 to turn on if its polarity doesn't match the Boot Flag.

- Negative: Amptek's SDD detectors require negative HV.
- Positive: All other Amptek detectors require positive HV.

Note: This setting requires the DP5 to be power-cycled to take effect.

#### *ADC Invert*

This setting is only used in DP4 Emulation Mode. In PX4 Emulation Mode, the polarity is commanded via the configuration packet.

- Inverting: Used for SDDs and other positive-pulse preamps. (ADC Inversion, combined with the DP5's inverting front-end results in a non-inverting input.)
- Non-inverting: Used with negative-pulse preamps (all Amptek non-SDD preamps.)

Note: This setting requires the DP5 to be power-cycled to take effect.

#### *Fast Channel Shaping*

- Normal: The fast channel peaking time is 400nS (for a 20MHz clock) or 100nS (at 80MHz).
- 4x Slower: The fast channel peaking time is 1.6uS (for a 20MHz clock) or 400nS (at 80MHz).

Note: This setting requires the DP5 to be power-cycled to take effect.

#### *Spectrum Offset*

- None: No spectrum offset is applied – the spectrum zero is derived solely from BLR.
- Use Offset: The Boot Option 'Spectrum Offset' is added to BLR. This shifts the spectrum left or right along the horizontal axis. This permits channel "zero" to have "zero" energy.

Note: This setting is 'live' and will take effect immediately. To change the spectrum offset, set this option to 'Use Offset', click 'OK', then 'Set DP5 Boot Flags.' Next, read the boot flags again by selecting the 'Get Boot Options from DPP' button. This will enable the 'DP5 Spectrum Offset' box, where the offset channel can be entered and set.

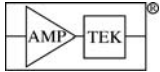
#### *Peak Detect*

- Max only (normal operation): This is the correct setting for normal operation.
- Max and min: This allows the peak detect (and MCA) to capture local minima of the shaped pulse stream, in addition to local maxima. This is useful for capturing the 'noise Gaussian' for determining the true spectrum zero. (The slow threshold must be set very low to accomplish this.)

Note: This setting is 'live' and will take effect immediately. It is also volatile – it will reset to 'Max only' the next time the DP5 is powered on.

#### *MCA Channel*

- Slow channel (normal operation): This is the correct setting for normal operation.



- o Fast channel: This sets the source for the MCA to the fast channel, rather than the slow channel. The fast channel does not have BLR or a pole-zero, but this setting does allow some insight into the operation of the fast channel.

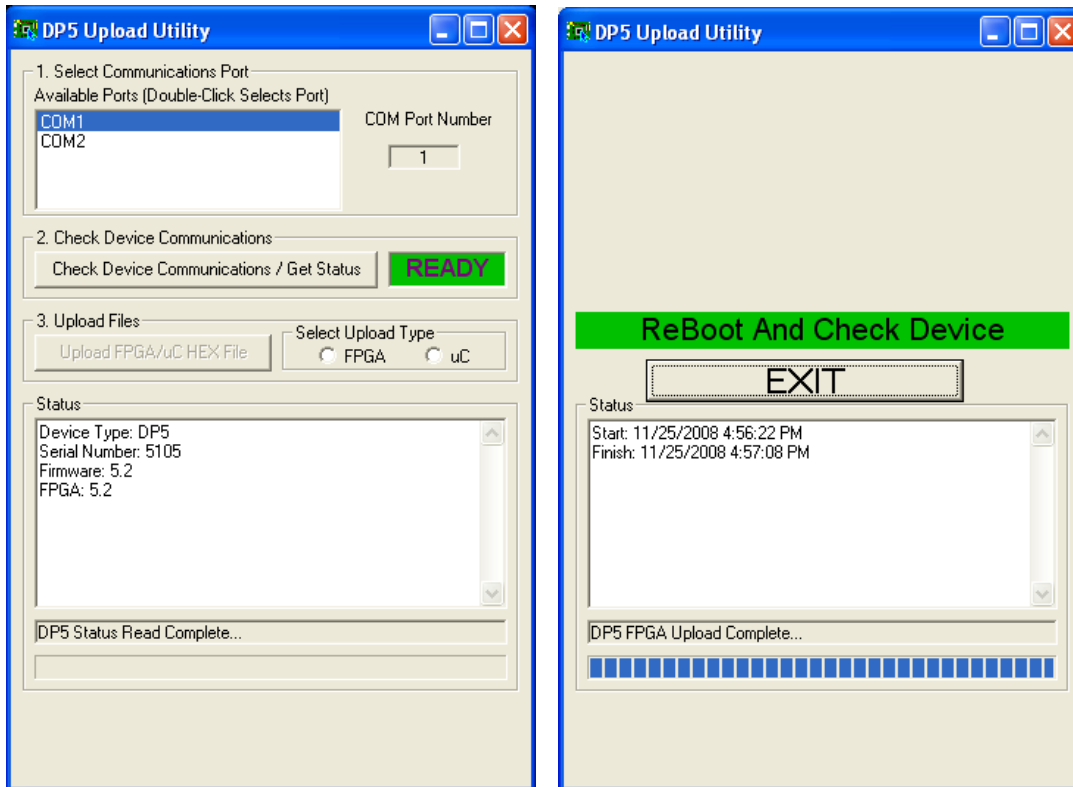
Note: This setting is 'live' and will take effect immediately. It is also volatile – it will reset to 'Slow channel' the next time the DP5 is powered on.

### 7.4 UPLOAD MANAGER

One of the advantages of the DP5 inside of the X-123SDD is the ability to upload new FPGA and microcontroller firmware through the RS232 interface. An FPGA upload takes approximately 40 seconds and a microcontroller code upload takes around 3 seconds.

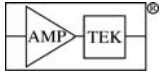
#### To upload updated firmware:

1. New firmware files will need to be acquired, either via email from Amptek, or via the Amptek.com website.
2. Install the DP5Loader application from the Amptek CD. The installer is located at \Additional DPP Software\DP5\DP5 Upload Utility\SWSETUP\SETUP.EXE on the CDROM.
3. Connect the 9-pin-to-stereo-plug RS232 cable that came with the DP5 between a PC serial port and the DP5, and apply power to the DP5.
4. Run DP5Loader.EXE (which you installed in Step #2).
5. Double-click the COM port that the DP5 is connected to.
6. Click 'Check Device Communications / Get Status'. This will show 'READY' if it successfully finds the DP5, or ERROR if not. For example, these screen shots show updating a DP5 from FW 5.02 & FP 5.02 to FW 5.03 & FP 5.03:

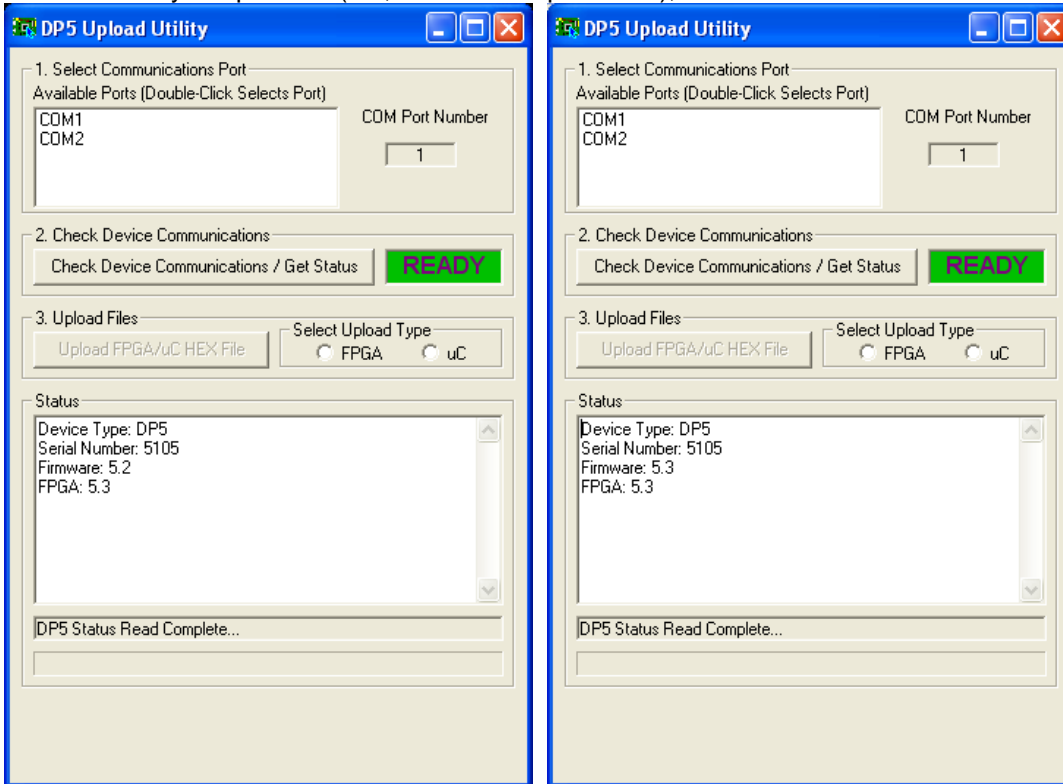


7. Select upload type "FPGA".
8. Click the 'Upload FPGA/uC HEX File' and select the FPGA programming file ('\_dp5\_fpga\_v502.mcs' for example. All FPGA programming files have an .mcs extension.) It will take around 40 seconds to program at 115kbaud.

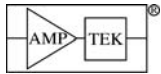




9. The program says 'Reboot and check device'. **Power cycle the DP5.**
10. Click 'Exit.'
11. Run DP5Loader.EXE again.
12. Click 'Check Device Communications / Get Status'. It should now show the version number of the FPGA you uploaded (5.3, for the example below), and the old Firmware version.



13. Select upload type "uC".
14. Click the 'Upload FPGA/uC HEX File' and select the microcontroller programming file ('dp5\_uC\_v503.hex' for example – uC programming files have the .hex extension.) It will take around 4 seconds to program at 115kbaud.
15. The program says 'Reboot and check device'. **Power cycle the DP5 again** and exit the program.
16. Run DP5Loader.EXE again and click 'Check Device Communications / Get Status' to confirm the Firmware & FPGA versions – in this example, Firmware 5.3 & FPGA 5.3. All done!



## 8 UNDERSTANDING THE X-123SDD

### 8.1 UNDERSTANDING THE COMPLETE SYSTEM

Figure 8-1 is a block diagram of the X-123SDD. The key elements include (1) the detector, (2) the preamplifier, (3) the digital pulse processor, (4) the power supplies, (5) the packaging or enclosure for the system, and (6) the computer running software for instrument control, data acquisition, and data analysis. All X-ray spectroscopy systems contain these basic elements.

This section provides a summary of the purpose and operation of each of these elements, to assist users in understanding how to optimize the system configuration for any particular application. Details on the electrical interfaces and on software configuration settings are given in later sections.

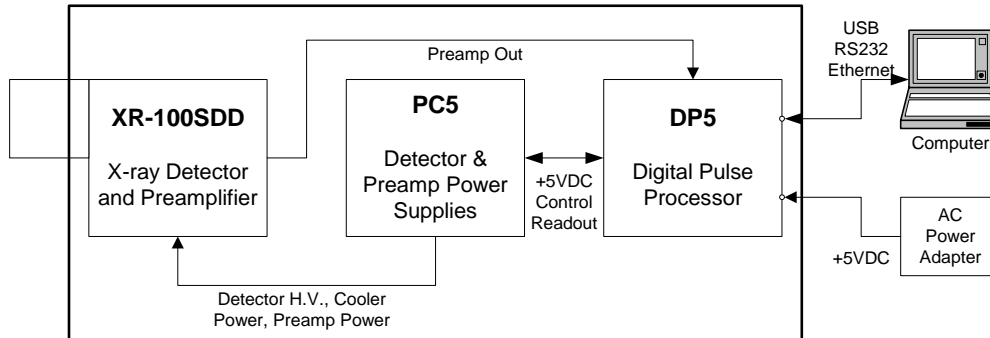


Figure 8-1. Block diagram of the X-123SDD.

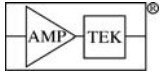
Amptek, Inc. provides a family of spectroscopy products, all built around the basic elements illustrated in Figure 8-1. In brief, all include a detector, a preamp, a DPP, and power supplies. There are several different detectors, optimized for different applications. This includes Si-PIN, SDD, and CdTe diodes, along with scintillators/PMT units. The components are also available in several packaging options: integrated in a single package (as in the X-123 or GammaRad), as a separated preamp and signal processor/power supply (XR100 and PX4), or as printed circuit boards which users integrate into their own products. The signal processor can also be used with other detectors, e.g. proportional counters. Amptek now provides two generations of the core digital processor, the DP4 and DP5, packaged into the PX4 and PX5 (PX5 will be available soon).

The discussion in this section applies to all of the products which are based on the DP5 generation of digital processor, including the PX5, X-123SDD, etc. We will refer to the digital processing logic as the “digital pulse processor” or DPP, which may be the DP5 circuit board itself or the same logic running in the PX5. The first generation DP4 family is very similar in overall operation, although there have been many enhancements to performance and many changes to the interface details.

#### Theory of Operation

When an X-ray photon interacts in the detector, it generates electron-hole pairs. The signal charge  $Q_{sig}$  is proportional to the energy deposited: in silicon, one electron-hole pair is formed for each 3.6 eV deposited. A 5.9 keV X-ray, for example, produces about 1,640 electron hole pairs ( $2.6 \times 10^{-16}$  coulombs). The signal processing electronics measures the charge (and therefore the energy) deposited by each X-ray. A second stage of the electronics accumulates the results of many such discrete interactions, producing the energy spectrum, a histogram showing how many interactions deposited energy within many energy bins. The electronics also measure the total count rate. Figure 8-2 shows the key components in the system: the detector, the preamplifier, a shaping amplifier, and pulse analysis electronics.

- The detector is a diode, with a bias voltage applied to sweep the electron-hole pairs into the electronics. Each X-ray interaction produces a pulse of current through the detector, input to the charge sensitive preamplifier (a.k.a. the preamp). In Amptek’s XR100 family of products, the detector is mounted on a thermoelectric cooler. This reduces the electronic noise significantly, without the need for cryogenic cooling. The silicon drift diode (SDD) is a special type of diode, using a unique electrode structure to improve performance.



- The preamp produces a voltage step, with magnitude  $\Delta V$  proportional to the deposited charge. In the XR-123SDD, the conversion gain is 1 mV/keV, so these steps are a few millivolts in magnitude. Each preamp step rides on a baseline which can be several volts and has significant random noise.
- The shaping amplifier converts the preamplifier output signal into a form suitable for measurements, producing an output pulse with pulse height  $V_{peak}$  proportional to the deposited charge  $Q$ . Since deposited energy is proportional to pulse height, pulse height analysis can be used to analyze the energy spectrum. The shaping amplifier has three primary roles: (1) separate the  $\Delta V$  step from the larger but slowly varying baseline from the preamp, (2) amplify the  $\Delta V$  values into a range which can be digitized accurately, and (3) filter out the random electronic noise.

In Amptek's DPP family, the shaping is done digitally since digital filters provide significant performance advantages over more traditional analog shaping schemes. The preamp output undergoes some analog filtering (to enable accurate digitization) and this is digitized at a high rate (20 to 80 MHz). This waveform then passes through a digital filter which implements the shaping and peak detect functions. This is implemented in an FPGA in near real-time via pipeline logic.

- The pulse analysis electronics use the measured peak heights to produce the histogram (or spectrum). This component includes logic to accept or reject events, using various criteria, to measure count rates, and to produce several auxiliary outputs.

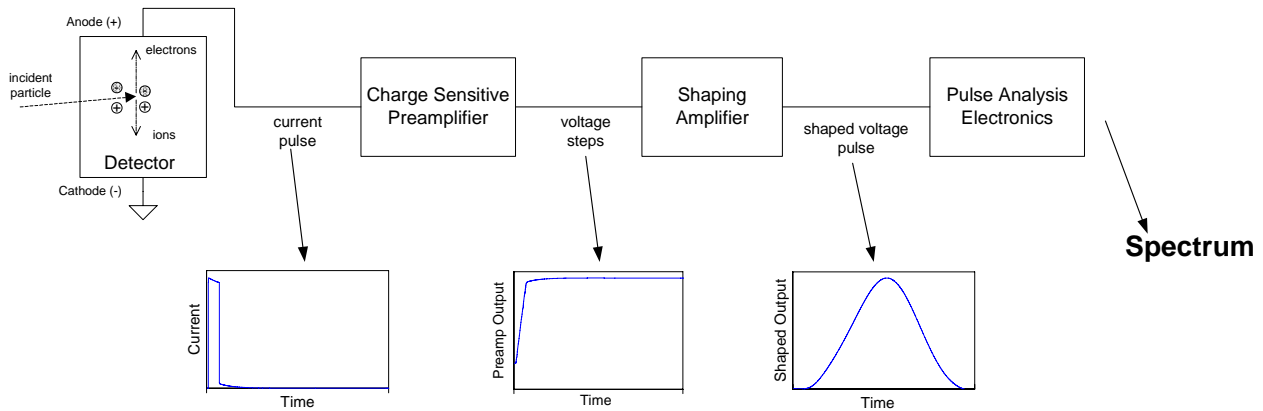


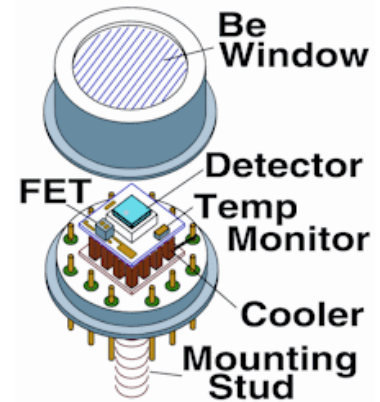
Figure 8-2. Schematic diagram of an X-ray spectroscopy system. Typical outputs from each stage of the processing electronics (for a single pulse) are also sketched .

Along with these “core” components, a complete system must include power supplies, hardware and software to data acquisition, data analysis, and instrument control, and mechanical packaging. The X123 integrates all of these functions into a compact, low power complete system.

## 8.2 UNDERSTANDING THE DETECTOR AND PREAMPLIFIER

The heart of the X-123SDD is the detector hybrid, shown to the right. The detector is a diode. In the X-123SDD, the detector is a silicon drift diode, a diode with a unique electrode structure. Amptek's other products utilize conventional, planar silicon PIN diodes or CdTe Schottky diodes. These diodes are available with areas of 5 to 25 mm<sup>2</sup> and thicknesses from 300 to 1000 μm.

The detector is mounted on a thermoelectric cooler, along with key preamplifier components, including the input FET. The cooler, which can achieve an 85°C temperature differential, reduces electronic noise without requiring cryogenics. A temperature monitor is also on the substrate, to control the temperature for stable operation. Vacuum is required inside the TO-8 package to achieve this ΔT. The heat extracted by the cooler is conducted to the mounting stud.



The detector is mounted behind a thin Be window (1/2 or 1/3 mil). An internal collimator is also located above the detector, to restrict the incident X-rays to the active volume of the detector.

### 8.2.1 Design and Operation

#### Detector Operation

Figure 8-3 shows sketches of a conventional Si-PIN photodiode (left) and a silicon drift diode (right). The CdTe Schottky diodes have the same structure as the Si-PIN. In the Si-PIN, there are two planar contacts with a uniform electric field between them. An X-ray interacts at some location, ionizing the Si atoms and producing electron-hole pairs. The electric field sweeps the carriers to their respective contacts, causing a transient current pulse  $I(t)$  to flow through the diode. The current is integrated onto the feedback capacitor  $C_F$ , producing an output voltage  $V(t) = \int I(t) dt$ .

The SDD uses a planar cathode but the anode is very small and surrounded by a series of electrodes. The SDD is cylindrically symmetric, so the anode is a small circle and the drift electrodes are annular. These electrodes are biased to create an electric field which guides the electrons through the detector, where they are collected at the anode, producing a transient current pulse  $I(t)$  just like the Si-PIN. The rest of the signal processing electronics is nearly identical to that used with the Si-PIN diode. The key difference is the small area of the anode keeps the capacitance very small and independent of detector area. This is important because the dominant noise source in silicon X-ray spectroscopy is voltage noise, which is proportional to the total input capacitance and increases at short shaping times. The SDD, with its low capacitance, has lower noise, particularly at very short shaping times.

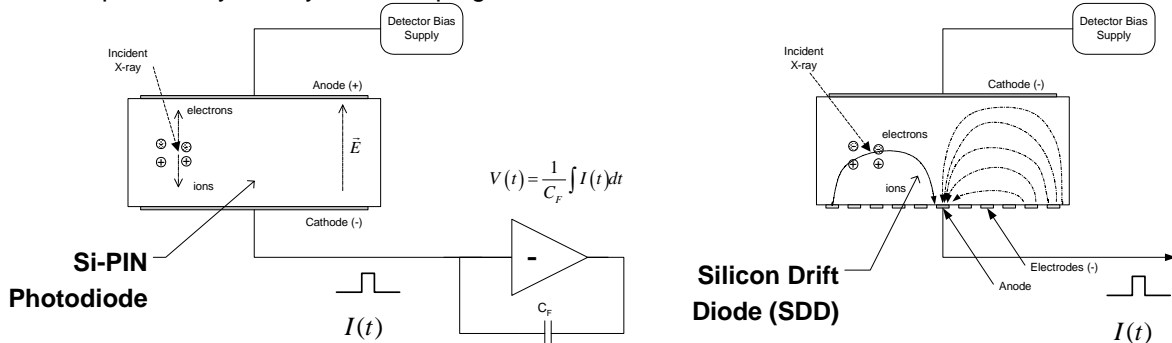
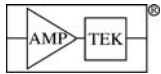


Figure 8-3. Sketch of conventional Si-PIN photodiode (left) and silicon drift diode (SDD) right.

#### Detector Reset

When a preamp integrates the input current, as sketched above, its output will eventually saturate. The X-123SDD uses reset circuit to periodically restore the input charge. Figure 8-4 (a) shows voltage steps from two interactions. The output is constant between steps but eventually the preamp output will saturate. The reset circuit then produces a current pulse to restore the output to its initial value. Figure 8-4 (b) shows the output of a reset preamp over a very long time: many small steps of a few mV each causes the output to



linearly approach the negative limit (-5V) in a time of several seconds. The reset pulse occurs so the output goes to the initial value (+5V) in a few  $\mu\text{sec}$ . Reset preamplifiers provide the minimum electronic noise and so are used in Amptek's lowest noise systems, including the X-123SDD. The very large transient created during reset can affect signal processing, so the DPP includes logic to "lock out" the effects of this reset.

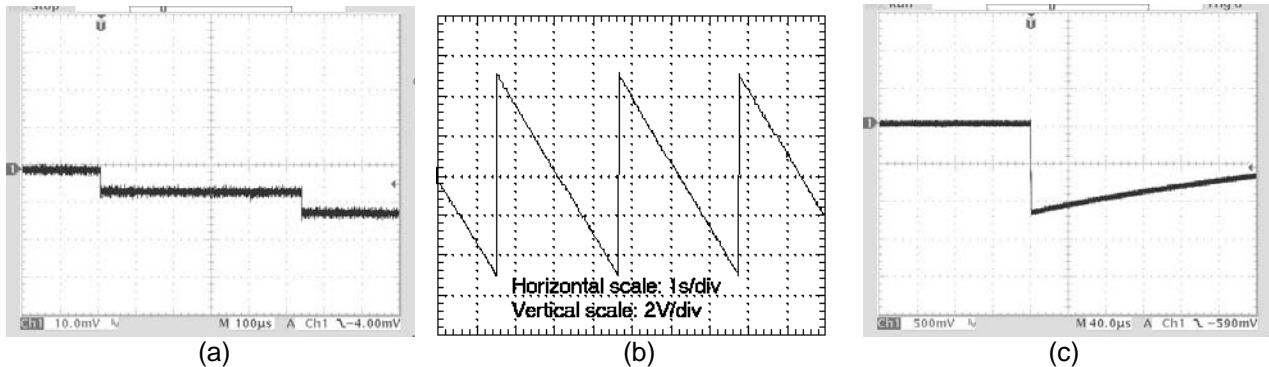


Figure 8-4. Oscilloscope traces showing typical preamplifier outputs, for reset preamps (a) and (b) and for continuous feedback preamps (c).

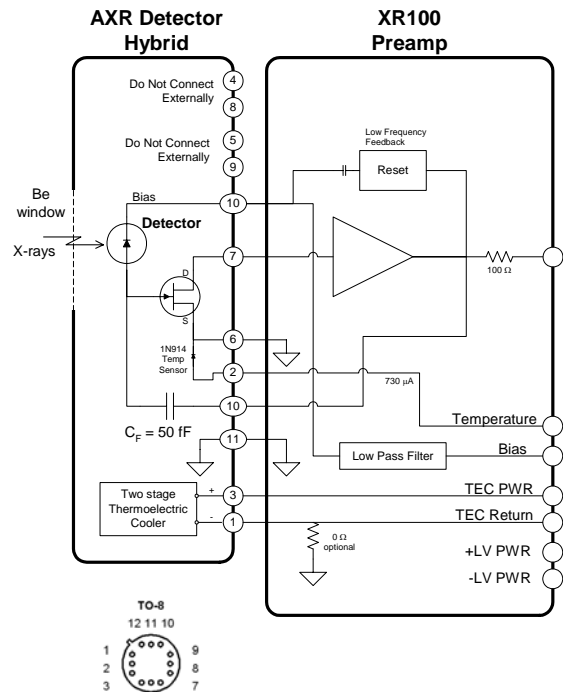
The traditional solution is to add a slow feedback path which restores the input to a value near ground. In the simplest case, a feedback resistor  $R_F$  is placed in parallel with the feedback capacitor  $C_F$  on which the current is integrated. After the voltage step  $\Delta V$  due to each signal interaction, the output slowly drifts back to its quiescent value, with the time constant of the feedback, as illustrated in Figure 8-4 (b). This time constant is 500  $\mu\text{sec}$  in this plot. The long time permits accurate integration of the total charge but causes the pulses to pile-up on one another. The feedback resistor adds electronic noise so is not used in the lowest noise systems. Some Amptek detectors replace the feedback resistor with a transistor. This offers lower noise than resistive feedback but does not match the performance of the reset preamps.

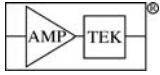
**Block Diagram**

Shown to the right is a generic block diagram of the detector and preamplifier in Amptek's XR100 family. All of the detectors (SiPIN, SDD, CdTe) share the same basic circuit. All of the preamps (XR100, the preamp boards in the X123, the OEM preamps) also have the same circuit diagram, though the pinouts differ. The reset circuits, bias polarity and magnitude, value of  $C_F$ , and other details will depend on the configuration.

**Notes**

- Pins 4, 5, 8, and 9 of the AXR are given as "Do Not Connect". These are unused in some units but are used in others.
- Pin 11 of the hybrid is the ground of the AXR case and should ground the preamp. The FET source is usually connected to this.





### 8.2.2 Performance

#### Energy Resolution

The energy resolution is one of the most important performance parameters in a spectrometer: two X-ray lines separated by more than the resolution can be separately identified. There are general scaling rules which are useful to understand when one is selecting a detector and optimizing system configuration. The resolution  $\Delta E$  usually expressed in eV FWHM and is given by

$$\Delta E^2 = ENC^2 + E_{FANO}^2$$

where ENC is the equivalent noise charge and  $E_{FANO}$  is Fano broadening. Fano broadening arises from statistical fluctuations in the interaction of the X-ray with the silicon. It is a fundamental limit of a material. In silicon, it is 118 eV FWHM at 5.9 keV and scales as  $\sqrt{E}$ . This is the resolution of a noiseless signal processor. Figure 8-5 shows the resolution of a spectrometer versus energy for an SDD.

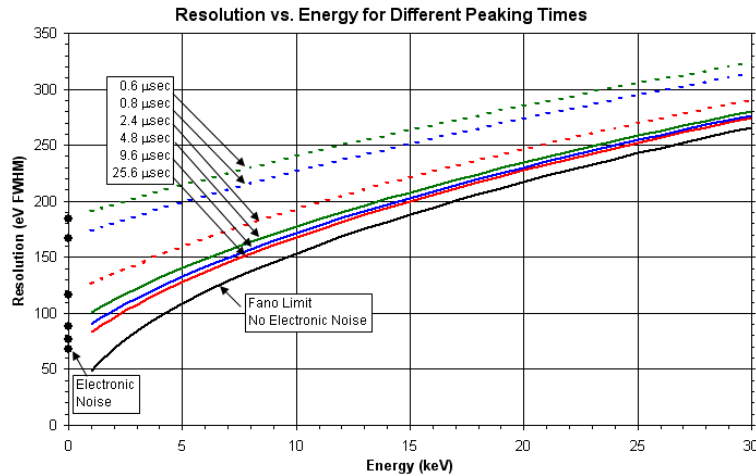


Figure 8-5. Plot showing resolution versus energy and time constant for an SDD at maximum cooling.. A Si-PIN exhibits a similar set of curves but the resolution degrades more rapidly at short peaking times.

The electronic noise is given by

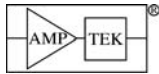
$$ENC^2 = C_{in}^2 \left( \frac{kTA_{\delta}}{\tau_{peak}} \right) + (A_{pink}) + (I_{dark} A_{step} \tau_{peak})$$

where  $C_{in}$  is the detector capacitance,  $\tau_{peak}$  is the peaking time of the signal processor,  $T$  is the temperature,  $I_{dark}$  is the leakage current through the diode, and  $A_{\delta}$ ,  $A_{pink}$ , and  $A_{step}$  are characterize the electronics (including terms due to the preamplifier and to the shaping amplifier). The key points are:

- At short peaking times, the noise increases rapidly with capacitance and increases as the peaking time is reduced. For Si-PIN diodes, the capacitance scales with area, so large area detectors exhibit more noise. For SDDs, the capacitance is much lower and nearly independent of area. This noise is only weakly dependent on temperature.
- At long peaking times, the noise increases with peaking times and with leakage current. Since leakage current increases exponentially with temperature, reducing temperature helps dramatically.
- There will always be some peaking time at which the noise is a minimum, where the delta and step terms are equal. There is no advantage to operating at a longer peaking time. The optimum time constant is shorter for lower capacitance and longer for low leakage currents.

#### High Count Rates

Each interaction produces a pulse. If a second interaction occurs after a very brief period of time, the two pulses overlap in time. This pulse pile-up may lead to a single distorted pulse, in which the pulse height of neither can be measured, and may lead to pulses which are detected. Because the timing of the X-ray emission is stochastic, there is always some probability that pulses will overlap. This probability obviously



increases at high count rate. The dead time is related to the peaking time, so to operate at high count rates, a short peaking time is desirable. As the previous section showed, short peaking times lead to increased electronic noise so there exists a trade-off, depicted in the figure below. One should not operate beyond the “maximum output count rate” curve.

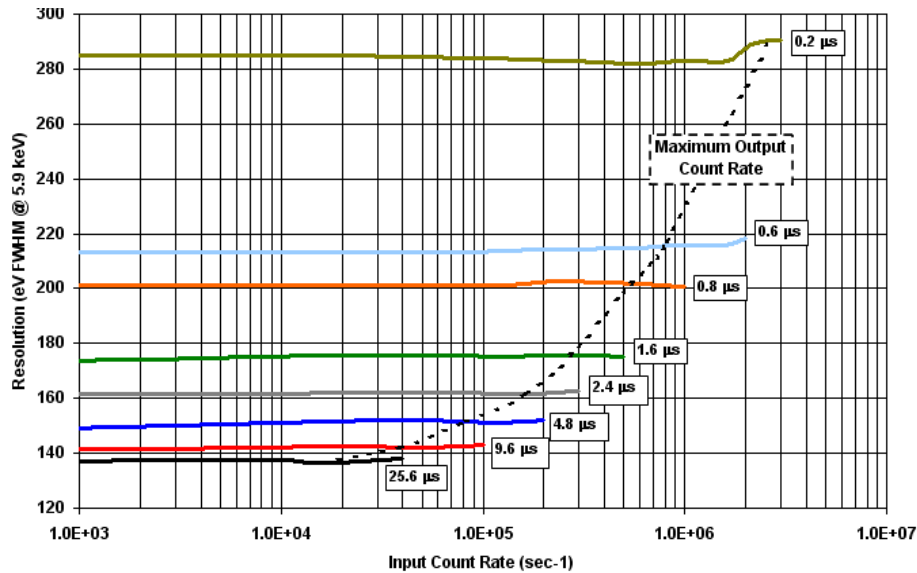


Figure 8-6. Plot showing resolution versus count rate, as a function of peaking time, measured at 5.9 keV.

*Sensitivity*

Figure 8-7 shows the sensitivity of the SDD as a function of energy. The efficiency is >25% from approximately 1 to 25 keV. At lower energies, the efficiency is limited by the Be window: lower energy X-rays are stopped in the window. At higher energies, the efficiency is limited by the interaction probability in the silicon: many X-rays pass through without interacting.

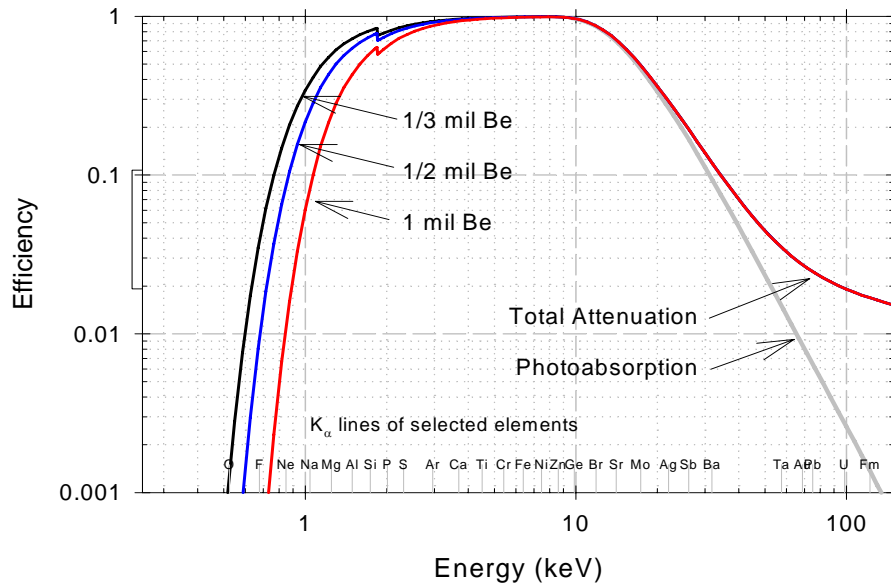
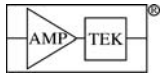


Figure 8-7. Plot showing the efficiency as a function of energy for the SDD

The SDD can certainly be used outside of the 1 to 25 keV range but one must correct for the losses. At low energies, accurate correction is difficult. Attenuation in air is very significant; the data in Figure 8-6 neglect air losses, and at 1 keV, only 1 cm of air will stop 90% of the X-rays. The geometric area of the detector is obviously important in determining the total or absolute sensitivity of a detector.



## X-ray Spectra

Understanding and analyzing X-ray spectra are quite complex, because many different factors become important. These are discussed in detail in many references in the literature. For the user trying to configure a spectrometer, it is important to recognize that the configuration impacts some aspects of the spectrum, while many other spectral features arise due to the physics of radiation interactions. Figure 8-8 shows a typical X-ray spectrum, from X-ray fluorescence. A 30 kVp X-ray tube with Ag anode was used to excite a sample of stainless steel, and the spectrum measured by an X-123SDD.

The dominant features are the photopeaks due to the characteristic X-rays emitted by the major constituents in the sample. The largest peak is due to the Fe  $K_{\alpha}$  line, as expected from steel. The other major constituent elements (Cr, Ni, and Mo) also show clear  $K_{\alpha}$  and  $K_{\beta}$  peaks. These peaks are essentially Gaussian in shape. Their width, as discussed above, is due to Fano broadening and electronic noise (the noise is much more important for Cr than for Mo).

There are several second order features which are apparent. The red arrows point to “escape peaks”: each of the primary peaks has an escape peak which is 1.45 keV lower in energy. When an X-ray stops in the silicon diode, all of the energy is usually deposited in the diode’s active volume. However, sometimes the interaction will produce a silicon characteristic X-ray (with energy 1.45 keV) and this may escape the detector volume. The energy deposited thus does not equal the incident energy. There are several such scattering processes, leading to a variety of spectral features, including both peaks and continua. The green arrows point to peaks arising from materials near the detector but not in the steel. This includes Ar (a major constituent of air) and Al.

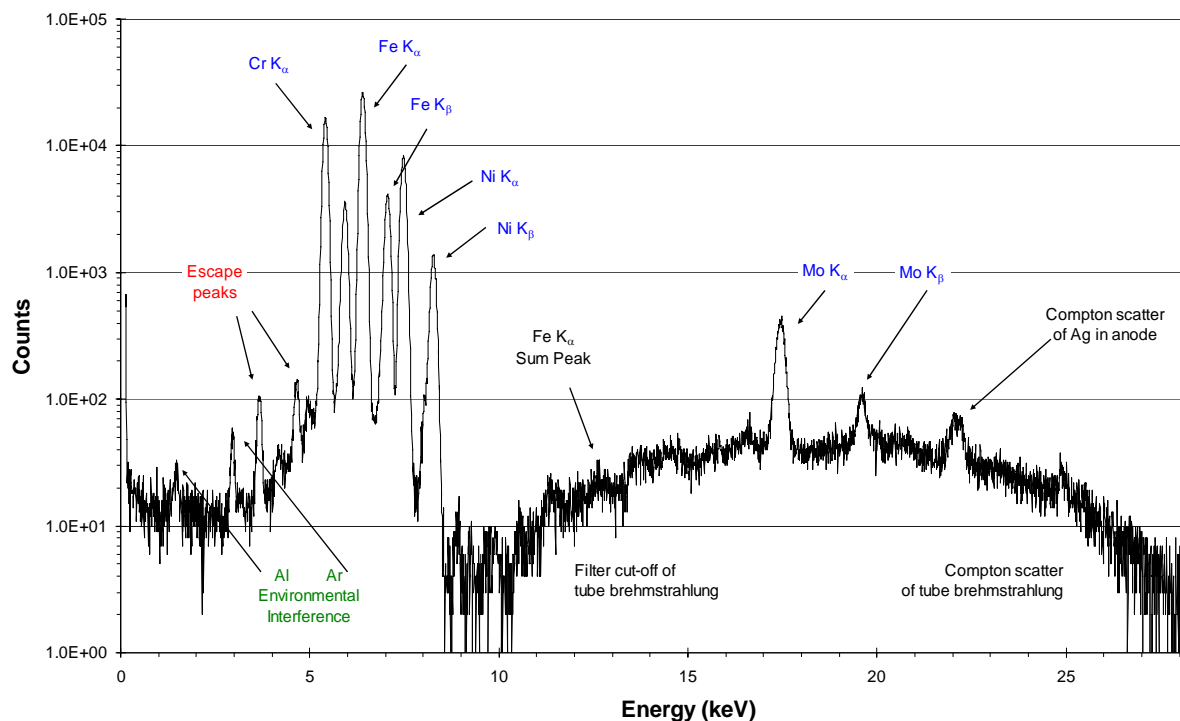
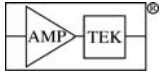


Figure 8-8. Typical spectrum of characteristic X-rays emitted by a sample of stainless steel, irradiated by a 30 kVp X-ray tube.

The X-ray tube emits X-rays at both the characteristic energy of the Ag anode and over a broad Bremsstrahlung continuum. Some of these X-rays Compton scatter from the steel. This leads to the peak just below 22 keV (Compton scatter from the Ag line) and the continuum. In addition, one can observe a very weak peak just above 12 keV due to pile-up of the Fe  $K_{\alpha}$  X-rays. Complex spectra such as these are to be expected in X-ray spectroscopy.





## 8.3 UNDERSTANDING THE DIGITAL PROCESSOR

### 8.3.1 Major Function Blocks

Figure 8-9 shows how a Digital Pulse Processor (DPP) is used in the complete signal processing chain of a nuclear instrumentation system and its main function blocks. The DPP digitizes the preamplifier output, applies real-time digital processing to the signal, detects the peak amplitude (digitally), and bins this value in its histogramming memory, generating an energy spectrum. Pulse selection logic can reject pulses from the spectrum, using a variety of criteria. The spectrum is then transmitted over the DPP's interface to the user's computer.

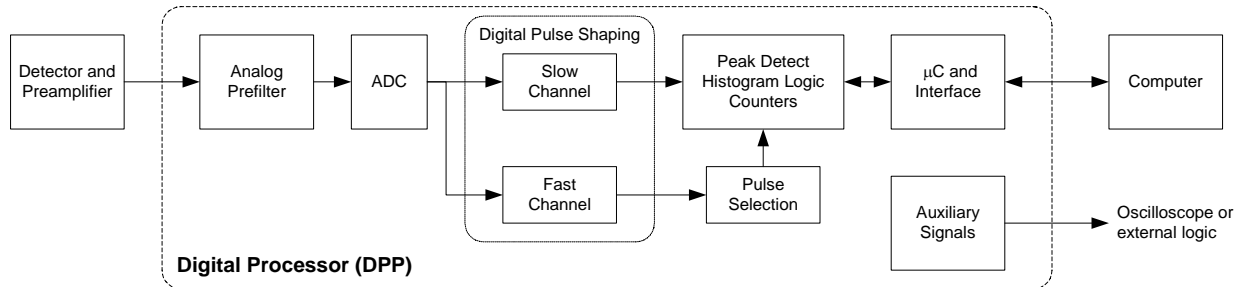


Figure 8-9. Block diagram of a Digital Pulse Processor (DPP) in a complete system.

**Analog Prefilter:** The input to the DP5 is the output of a charge sensitive preamplifier. The analog prefilter circuit prepares this signal for accurate digitization. The main functions of this circuit are (1) applying appropriate gain and offset to utilize the dynamic range of the ADC, and (2) carrying out some filtering and pulse shaping functions to optimize the digitization.

**ADC:** The 12-bit ADC digitizes the output of the analog prefilter at a 20 or 80 MHz rate. This stream of digitized values is sent, in real time, into the digital pulse shaper.

**Digital Pulse Shaper:** The ADC output is processed continuously using a pipeline architecture to generate a real time shaped pulse. This carries out pulse shaping as in any other shaping amplifier. The shaped pulse is a purely digital entity. Its output can be routed to a DAC, for diagnostic purposes, but this is not necessary.

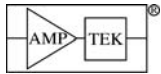
There are two parallel signal processing paths inside the DPP, the “fast” and “slow” channels, optimized to obtain different data about the incoming pulse train. The “slow” channel, which has a long shaping time constant, is optimized to obtain accurate pulse heights. The peak value for each pulse in the slow channel, a single digital quantity, is the primary output of the pulse shaper. The “fast” channel is optimized to obtain timing information: detecting pulses which overlap in the slow channel, measuring the incoming count rate, measuring pulse risetimes, etc. and to obtain

**Pulse Selection Logic:** The pulse selection logic rejects pulses for which an accurate measurement cannot be made. It includes pile-up rejection, risetime discrimination, logic for an external gating signal, etc.

**Histogram Memory:** The histogram memory operates as in a traditional MCA. When a pulse occurs with a particular peak value, a counter in a corresponding memory location is incremented. The result is a histogram, an array containing, in each cell, the number of events with the corresponding peak value. This is the energy spectrum and is the primary output of the DPP. The unit also includes several counters, counting the total number of selected pulses but also counting input pulses, rejected events, etc. Auxiliary outputs include eight different single channel analyzers, and both a DAC output and two digital outputs showing pulse shapes selected from several points in the signal processing chain.

**Interface:** The DP5 includes hardware and software to interface between these various functions and the user's computer. A primary function of the interface is to transmit the spectrum to the user. The interface also controls data acquisition, by starting and stopping the processing and by clearing the histogram memory. It also controls certain aspects of the analog and digital shaping, for example setting the analog gain or the pulse shaping time. The DPP includes USB, RS232, and Ethernet interfaces.

The DP5 also includes a power interface. It takes a loosely regulated 5VDC input and generates the various levels required by the circuitry (+/- 5.5V, 3.3V, 2.5V).



### 8.3.2 Analog Prefilter

The DP5 was designed to process signals coming directly from a charge sensitive preamplifier used with solid-state radiation detectors. These signals typically have (1) a small amplitude, in the range of a few mV, (2) a fast rise (tens of nsec to  $\mu$ sec), and (3) the small pulses “ride up” on one another as the signal pulses accumulate. These steps can be seen in the top traces of Figure 8-10 and are not suitable to be directly digitized, due to the small amplitude (a few mV) over the large range (many volts). The analog prefilter prepares the signal so it can be accurately digitized.

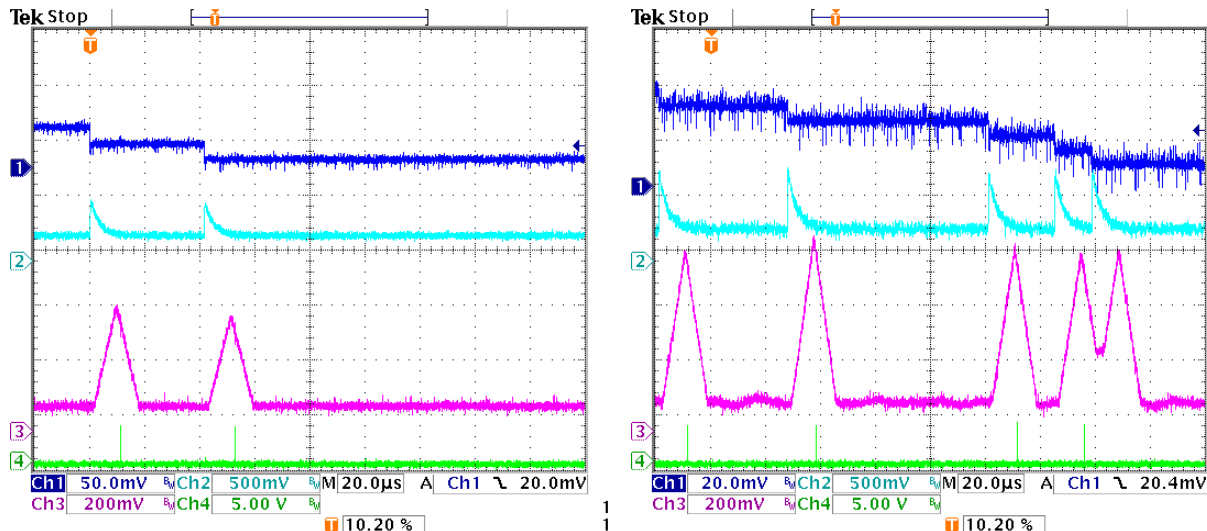


Figure 8-10. Oscilloscope traces illustrating the signal processing. The dark blue trace on top shows the output of the preamplifier: a series of “steps” of a few millivolts, spaced randomly in time. High frequency white noise is clearly superimposed. The traces on the left (right) were measured with 60 (5.9) keV X-rays. The signal to noise ratio is clearly much degraded on the right. The light blue traces show the output of the analog prefilter, with its 3.2  $\mu$ sec pole. The magenta trace shows the shaped output: it is the peak of this which is detected and is binned in the spectrum. The green trace is a logic output indicating that a valid peak has been detected.

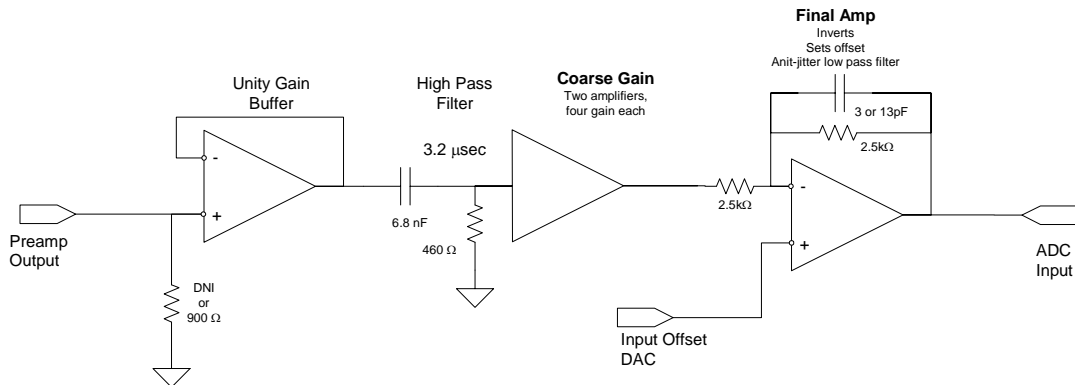
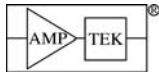


Figure 8-11. Block diagram of the analog prefilter in the DP5.

The prefilter implements three functions: (1) it applies a high pass filter with a 3.2  $\mu$ sec time constant, so that the pulses no longer “ride up” on one another, (2) it applies a coarse gain so that the largest pulses are approximately 1 V (to maximize the ADC resolution), and (3) it applies a DC offset so that the signal always falls within the range of the unipolar ADC. The output of the prefilter can be seen as the cyan color trace in Figure 8-10 and consists of a series of pulses with a fast rise, 3.2  $\mu$ sec decay, a baseline of a few hundred millivolts, and maximum values of around 1V. The prefilter can accommodate pulses of either polarity, inverting the signals digitally. In the X-123SDD, the analog prefilter of the DP5 is configured for use with Amptek’s XR100CR family of detectors: solid state X-ray detectors with a reset preamplifier. The DP5 can certainly be used with other detectors, but this will most often require changing the analog prefilter settings or circuit changes.



*System Gain*

The system conversion gain is expressed in units of channels/keV: it gives the MCA channel number in which a particular energy peak will occur. It is the product of three terms: (1) the conversion gain of the charge sensitive preamplifier (in units of mV/keV), (2) the total gain of the voltage amplifier (the product of coarse gain and fine gain), and (3) the conversion gain of the MCA (channels per mV).

For Amptek's XR100CR detectors, the preamp conversion gain is typically 1 mV/keV. The MCA's conversion gain is given by the number of channels selected (for example, 1024) divided by the voltage corresponding to the peak channel. In Amptek's digital processors, this is approximately 950 mV. The DP5 gain is the product of the coarse and fine gains. For example, if the fine gain is 1.00 and the coarse gain is 66.3, then the system conversion gain is  $(1 \text{ mV/keV})(66.3)(1.00)(1025 \text{ ch/950 mV})=71.5 \text{ channels/keV}$ . The inverse of this is the MCA calibration factor, 14 eV/channel. The full scale energy is 1024 channels/71.5 channels per keV, or 14.3 keV. Note that these values are approximate. Due to manufacturing tolerances in the feedback capacitors, in resistors, etc the actual gain can vary by several percent, which will cause a noticeable shift in the spectrum. These calculations should be used for system design and for initial configuration. For any given system, the gain will need tuning and the spectrum will need to be calibrated.

For systems other than Amptek's XR100 series, the preamp conversion gain can be estimated. It is the product of three terms: (1) one over the energy required to create an electron hole pair in the detector ( $W$ ), (2) any internal detector gain, e.g. with a proportional counter or PMT, and (3) the preamp's conversion gain,  $q/C_F$ , where  $C_F$  is the feedback capacitance. For example, for a Xe proportional counter,  $W$  is 21.5 eV. At a gain of  $10^3$  and  $C_F=1 \text{ pF}$ , the conversion gain is  $(1/21.5 \text{ eV/pair})(10^3)(1.6 \times 10^{-19} \text{ C}/10^{-12} \text{ F})=7.4 \text{ mV/keV}$ .

*Reset and Continuous Preamplifiers*

Most spectroscopy detectors utilize a charge sensitive preamplifier, which precedes the analog prefilter in the DP5. A charge sensitive preamplifier produces a voltage proportional to the time integral of the current. The integrator will eventually saturate because the time integral of the current through the diode continues to increase. There are two methods used to keep the preamplifier output within range: resets and continuous feedback. Figure 8-4 (left) shows the output of a reset preamp over a very long time: many small steps of a few mV each causes the output to linearly approach the negative limit (-5V) in a time of several seconds. The reset pulse occurs so the output goes to the initial value (+5V) in a few  $\mu\text{sec}$ . Reset preamplifiers provide the minimum electronic noise and so are used in Amptek's lowest noise systems, including the XR100. The very large transient created during reset can affect signal processing, so the DPP includes logic to "lock out" the effects of this reset.

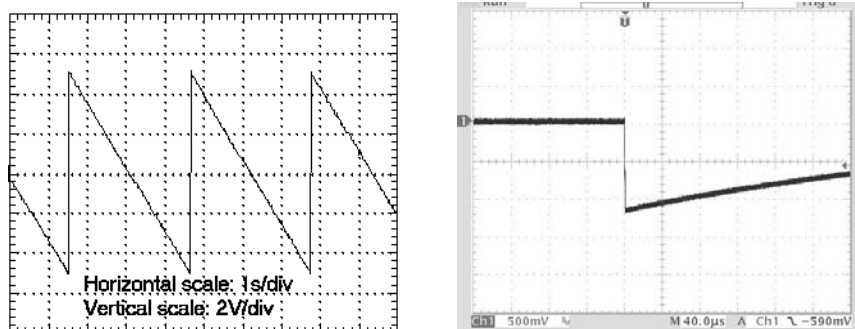
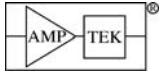


Figure 8-12. Oscilloscope traces showing typical preamplifier outputs, for reset preamps (a) and (b) and for continuous feedback preamps (c).

Another traditional solution is to add a slow feedback path which restores the input to a value near ground. In the simplest case, a feedback resistor  $R_F$  is placed in parallel with the feedback capacitor  $C_F$  on which the current is integrated. After the voltage step  $\Delta V$  due to each signal interaction, the output slowly drifts back to its quiescent value, with the time constant of the feedback, as illustrated in Figure 8-4 (b). This time constant is 500  $\mu\text{sec}$  in this plot. The long time permits accurate integration of the total charge but causes the pulses to pile-up on one another. The feedback resistor adds electronic noise so is not used in the lowest noise systems. Some Amptek detectors replace the feedback resistor with a transistor. This offers lower noise than resistive feedback but does not match the performance of the reset preamps.



### 8.3.3 Pulse Shaping

#### *Slow Channel*

The “slow channel” of the DPP is optimized for accurate pulse height measurements. It utilizes trapezoidal pulse shaping, with a typical output pulse shape shown in Figure 8-13. This shape provides a near optimum signal to noise ratio for many detectors. Relative to conventional analog shapers, the trapezoid provides lower electronic noise and, simultaneously, reduced pulse pile-up.

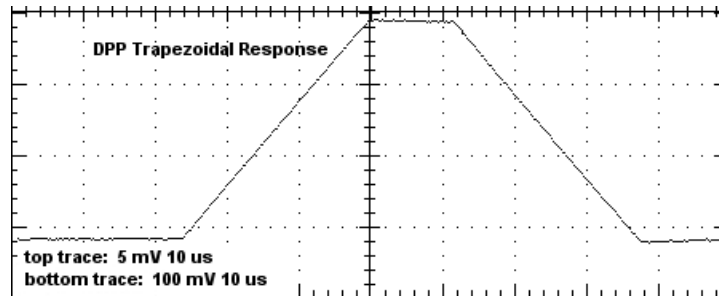


Figure 8-13. Pulse shape produced by the DPP.

The user can adjust the rise/fall time (the rise and fall must be equal) and the duration of the flat top over many steps. A semi-Gaussian amplifier with shaping time  $\tau$  has a peaking time of  $2.2\tau$  and is comparable in performance with the trapezoidal shape of the same peaking time. A DPP with  $2.4 \mu\text{sec}$  peaking time will be roughly equivalent to a semi-Gaussian shaper with a  $1 \mu\text{sec}$  time constant.

Adjusting the peaking time is a very important element in optimizing the system configuration. There is usually a trade-off: the shortest peaking times minimize dead time, yielding high throughput and accommodating high count rates, but the electronic noise usually increases at short peaking times. The optimum setting will depend strongly on the detector and preamplifier but also on the measurement goals. The electronic noise of a detector will generally have a minimum at some peaking time, the “noise corner.” At peaking times shorter or longer than this, there is more noise and hence degraded resolution. If this peaking time is long relative to the rate of incoming counts, then pulse pile-up will occur. In general, a detector should be operated at a peaking time at the noise corner, or below the noise corner as necessary to accommodate higher count rates.

If the risetime from the preamp is long compared with this peaking time, then the output pulses will be distorted by ballistic deficit. In this case, the trapezoidal flat top can be extended to improve the spectrum. The specific optimum timing characteristics will vary from one type of detector to the next and on the details of a particular application, e.g. the incoming count rate. The user is encouraged to test the variation of performance on these characteristics.

#### *Fast Channel*

The DPP’s “fast channel” is optimized to detect pulses which overlap in the “slow channel”. The fast channel is used for pile-up reject logic (rejecting pulses which are so closely spaced that they cannot be distinguished in the slow channel) and for determining the true incoming count rate (correcting for events lost in the dead time of the slow channel). The fast channel also utilizes trapezoidal shaping, but the peaking time is commensurate to either 100 nsec or 400 nsec. The oscilloscope traces in Figure 8-14 show the measured pulse shapes with a 100 nsec peaking time. As seen on the right, pulses which are separated by only 120 nsec are separately counted in the fast channel.

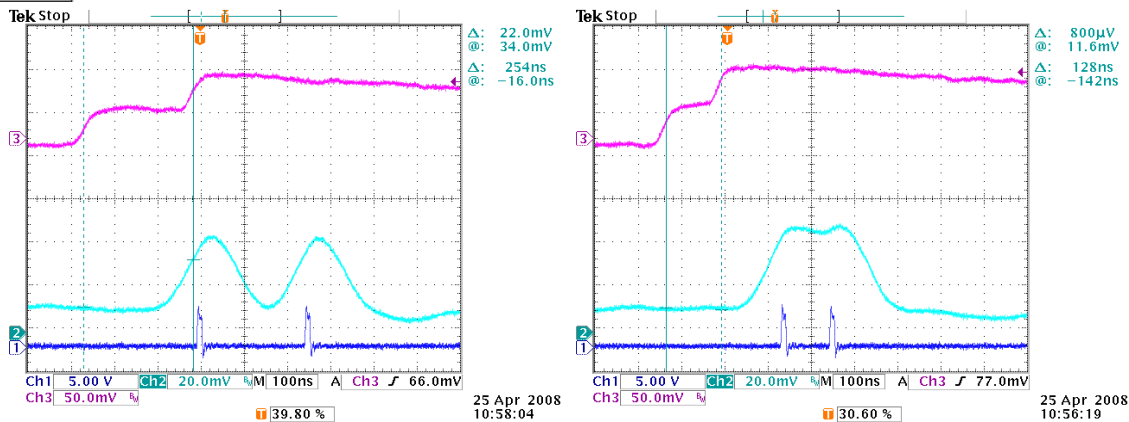
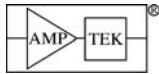


Figure 8-14. Oscilloscope traces showing operation of the DPP “fast channel”. The magenta trace at top shows the ADC input, the light blue trace shows the fast channel shaped output, and the dark blue trace shows the logic output which counts the fast channel events.

### Baseline Restoration

The pulse height is implicitly measured relative to a baseline. Any random fluctuation or systematic variation in the baseline, whether high frequency noise or a slow change, will degrade the pulse height measurement. The baseline is often assumed to be “ground”, but this is a somewhat ambiguous notion, since “ground” represents simply the reference for voltage measurements. If this baseline changes with time, count rate, or anything else, then distortions are introduced into measurements. In pulse height analysis, the spectrum will appear to shift, while in counting systems, the threshold will change. In practice, the most common baseline shift occurs with count rate.

The peak of the “baseline” of a digital processor has some significant differences from traditional analog shaping amplifiers. Because the DPP’s transfer function has a finite impulse response, after a pulse has passed through the processing pipeline it has no impact on the output. This is fundamentally different from an analog differentiator and results in vastly enhanced baseline stability at high count rates. However, unlike analog shapers the DPP has to establish a DC baseline, at all count rates, and in practice some shifts with count rate are observed.

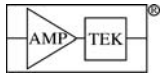
The DPP has an asymmetric baseline restorer with several different settings. The DPP BLR uses the negative peaks from random noise to determine the baseline. The negative-going noise peaks only occur in the absence of a signal, so if these are stable, then the baseline is stable, independent of counts. The BLR generally produces an offset comparable to the rms noise value. There are two independent parameters, UP and DOWN, each of which can be set to four values: Very Slow, Slow, Medium, and Fast. These are essentially slew rates in the baseline response. A setting of Very Fast for both UP and DOWN means that the BLR will respond very rapidly to any measured variation in the baseline. It must be stressed that the optimum setting depends strongly on the details of a particular application: the nature of the baseline drifts, etc. If the peaks are found to shift to lower channels at high count rates, then increase the UP slew rate or decrease the DOWN slew rate. If one observes occasional “bursts” in the system which cause the spectrum to shift to higher channels (often manifesting as bursts of noise above the threshold), then decrease the UP slow rate or increase the DOWN slew rate.

### 8.3.4 Pulse Selection

#### Thresholds

The DPP uses thresholds to identify pulses. Both fast and slow channels have their own independent thresholds. Noise is usually higher in the fast channel, and it is best to set the thresholds just above the noise, so they will be different in the two channels. The DPP uses the Slow Channel Threshold to identify events that should be added to the stored spectrum. Events with an amplitude lower than the Slow Channel Threshold are ignored – they do not contribute to the stored spectrum. The slow channel threshold is the equivalent of a low-level discriminator (LLD).

The Fast Channel Threshold also functions as an LLD and is used for several functions. (1) The rate of events over the fast threshold is the DPP’s measurement of the incoming count rate (ICR). (2) Pile-Up



Rejection (PUR) logic identifies events which overlap in the slow channel but are separated in the fast channel. (3) Rise Time Discrimination (RTD) uses the amplitude of the fast channel signal to measure the current at the beginning of a pulse. PUR and RTD are discussed in more detail below.

Properly setting these thresholds is very important for getting the best performance from the DPP. Under most circumstances, the thresholds should be set just above the noise, and the ADMCA software includes an “AutoTune” function to set these. Improperly set thresholds are responsible for a large number of problems reported by customers. If the fast channel threshold is too low, for example, and PUR is enabled, then every event will be rejected and so there appears to be no signal. If the slow channel threshold is too high, then it is also possible to reject all events.

#### *Pile-Up Rejection*

The goal of the pile-up reject (PUR) logic is to determine if two interactions occurred so close together in time that they appear as a single output pulse with a distorted amplitude. The DPP PUR uses a “fast-slow” system, in which the pulses are processed by a fast shaping channel in parallel with the slower main channel (both channels are purely digital). Though similar in principle to the techniques of an analog shaper, the pile-up reject circuitry and the dead time of the DPP differ in significant ways, resulting in much better performance at high count rates. First, the symmetry of the shaped pulse permits the dead time and pile-up interval to be much shorter. Second, there is no dead time associated with peak acquisition and digitization, only that due to the pulse shaping.

Figure 8-15 illustrates the operation of the DPP for pulses that occur close in time. Figure 8-15 (a) shows two events that are separated by less than the rise time of the shaped signal, while Figure 8-15 (b) shows two pulses that are separated by slightly longer than the rise time. In (a), the output is the sum of the two signals (note that the signal amplitude is larger than the individual events in (b)) and the events are said to be piled up. However, note that the analog prefilter outputs in (a) are separate. For a nearly triangular shape, pile-up only occurs if the two events are separated by less than the peaking time, in which case a single peak is observed for the two events. The interval used by the DPP for both dead time and pile-up rejection is the sum of risetime and the flat-top duration. If two events occur within this interval and pile-up rejection is disabled, then the single, piled-up value is in the spectrum. If pile-up rejection is enabled and two events are separated by more than the fast channel pulse pair resolution (120 nsec) and less than this interval, both are rejected. Events that exceed a threshold in the fast channel trigger the pile-up reject logic.

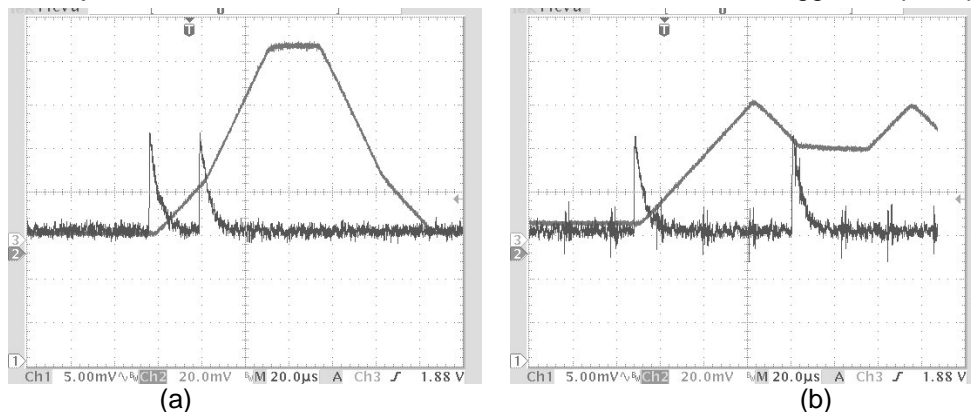
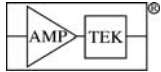


Figure 8-15. Oscilloscope traces illustrating the dead time and pile-up reject performance of the DPP

#### *Reset Lockout*

As discussed previously, many preamps use pulsed reset to prevent saturation of the preamp output. The reset generates a very large signal in the DPP, causing its amplifiers to saturate, registers to overflow, etc. The DPP therefore includes a reset detect circuit (which detects a very large, negative going pulse) and logic to lock out signal processing for some time following the reset, to give time for everything to return to stable values. The DPP permits the user to enable or disable reset (it should be disabled for preamps with continuous feedback). The user can also select the time interval during which the signal is locked out. If the interval chosen is too short, then there will be some distortion of the waveform (and thus spectrum) following reset. At high count rates the reset pulses occur frequently, and if the interval chosen is too long, then a significant dead time is observed.



### *Risetime Discrimination*

In some types of applications, it is important to separate pulses based on the duration of the transient current through the detector, into the preamplifier. For example, in some Si diodes there is an undepleted region with a weak electric field. A radiation interaction in this region will generate a signal current, but the charge motion is slow through the undepleted region. These interactions in this region can lead to various spectral distortions: background counts, shadow peaks, asymmetric peaks, etc. In CdTe diodes, the lifetime of the carriers is so short that slow pulses exhibit a charge deficit, due to trapping. These lower amplitude pulses distort the spectrum. In scintillators, pulse shape discrimination is sometime used to differentiate gamma-rays and neutrons. This pulse shape discrimination can be implemented using the DP5's RTD function. Most Amptek detectors do not require or benefit from RTD but for some it is quite useful.

Risetime discrimination rejects from the spectrum events with a long detector current, which leads to a slowly rising edge in the fast and slow shaped pulses. The DP5 implements RTD by comparing the peak height in the fast channel (which samples the charge integrated in the first 100 nsec) to the peak height in the slow channel (which samples the charge which is eventually integrated). If this ratio is sufficiently high, the risetime was fast and thus the pulse is accepted. If this ratio is low, the pulse is rejected. Because the fast channel is inherently much noisier than the slower shaped channel, an RTD threshold is also implemented on the shaped channel. Events which fall below this threshold (the "RTD Slow Threshold") are not processed by the RTD and are thus accepted (unless otherwise rejected by Pileup Rejection or some other criterion). Because RTD is most often needed on interactions deep in a detector, arising from high-energy events, low-amplitude events are unlikely to benefit from RTD rejection. These fall below the RTD Slow Threshold and are thus accepted.

### *Gate*

The gate input is used with external circuitry to determine if events should be included or excluded from the spectrum. The gate can be active high or active low (or disabled). If disabled, then this input is ignored and all events (which meet the criteria above) are counted. If active high (low), then if the gate input is high (low), the event is counted in the spectrum. When counts are gated off, the clock accumulation time counter is also gated off so that an accurate count rate can be determined. The timing of this gate input is important. If the gate input is active while the fast channel threshold is triggered, then the event is counted as a fast count. If the gate input is active when the peak detect is triggered, then the event is counted as a slow count and shows up in the spectrum. Note that the fast and slow channels are triggered at different times, since they have different shaping times.

### **8.3.5 MCA, MCS, Counters, and SCAs**

#### *Multichannel Analyzer*

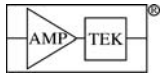
The MultiChannel Analyzer (MCA) operates like a conventional MCA, except that the input is already digitized. It detects the amplitude of the peak of the shaped pulse, using a digital peak detect circuit. If the selection logic indicates that the pulse is valid, then it increments the value stored at a memory location corresponding to the peak amplitude. The MCA supports 256, 512, 1024, 2048, 4096 or 8192 channels. The DP5 uses 3 bytes per channel, which allows up to 16.7M counts per channel.

The MCA hardware in the DP5 can be started and stopped by commands over the serial bus. It can also be preset to stop after a programmed acquisition time (with a minimum of 100 milliseconds) or after a programmed number of counts has been measured within the SCA8 region of interest (see below).

#### *Acquisition Time*

The DPP measures the spectrum and counts during the "acquisition time", which is also measured and reported. The acquisition time is the real elapsed time during which data are being acquired. The acquisition time clock is turned off during certain events, including data transfers over the serial bus and including reset intervals. If a reset preamplifier is used, and the DP5 is configured for a certain reset time period, then acquisition is shut down during the reset period and the acquisition clock is stopped. This acquisition time is measured using a typical 50 ppm crystal oscillator so is quite accurate. The true count rate should be computed using the actual acquisition time rather than the nominal data transfer time.

Data transfers occur based on an approximate real time clock in the host PC. For example, one might configure ADMCA to acquire data from the DP5 every second. When the data transfer occurs, the



acquisition time is shown and this will probably differ from the nominal “1 second”, due to the approximate clock and also due to reset losses. (A typical value is 1.05 second.) At high count rates, a reset preamp resets more often, and so there is less acquisition time per transfer. In this case, the acquisition time might become 0.85 seconds. On the screen, this time is displayed along with the fast counts and the slow counts during the same interval. The actual count rate is found by dividing the observed counts by the observed acquisition time, 0.85 seconds for this example.

### *Dead Time*

All nuclear spectroscopy systems exhibit a dead time associated with each radiation interaction. Following any interaction, there will be a time period during which subsequent pulses cannot be detected and will not contribute to the output counts. Because the timing of pulses is random, there is always some probability that pulses will occur in these dead time intervals, and therefore the output count rate ( $R_{out}$ ) measured by a system is always lower than the input count rate ( $R_{in}$ ). The measurement goal is to determine the incident spectrum and count rate, which requires correcting for these losses.

The dead time characteristics of a digital processor differ considerably from those of more traditional analog systems. This is discussed in some detail in an Amptek application note and a research publication. Some key points are:

- The deadtime per pulse of a digital processor is lower than that of a comparable analog system. There is no deadtime associated with acquiring the peak (this is termed simply the deadtime in an analog MCA and often dominates system deadtime) and the deadtime per pulse is greatly reduced due to the finite impulse response of the shaping.
- The best way to determine the incoming count rate is to directly measure it, using the DP5's fast channel. The accuracy and precision of this method are much better than that obtained using livetime clocks, which are traditional for analog systems, under most circumstances.
- The ADMCA software estimates the DP5 deadtime by comparing the count rates in the fast and slow channels. We recommend keeping this value below 50%. The DP5 operates at higher deadtime losses and can yield very accurate results, but great care is required in configuring the system and interpreting the count results.

### *Counters*

The DPP has several counters which are started and stopped at the same time as the spectrum. This includes the “fast channel counter”, which records all fast channel events which exceed the fast channel threshold. Note that there is no upper limit, and that none of the pulse selection logic applies (this is gated off during reset and data transfer). The slow channel counter records all events which are recorded in the spectrum. Note that there is an upper limit: events exceeding the maximum pulse height channel are not in the spectrum, hence not in the slow counts. The full pulse selection logic applies (PUR, RTD, etc).

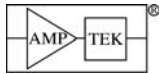
An additional counter records those events rejected by PUR and RTD. This is generally not of direct use but can be a “quality assurance” value by which one can verify system operation. The DP5 also includes an external counter, an external TTL input to a counter which is started and stopped at the same time as the other counters. This is useful if, for example, one has a second detector and the counts at the same time are of interest.

### *Single Channel Analyzers*

The DP5 contains eight single channel analyzers (SCAs). Each SCA has an upper and a lower threshold. If an event occurs with a shaped output within the range defined by these thresholds, and is accepted by PUR and the other pulse selection logic, then a logic pulse is generated and is output to the AUX connector, where it can be connected to external hardware. These are commonly used when a user needs to record count rates at a much higher time resolution than the 100 millisecond minimum for spectrum acquisition and only needs the rates within a few energy bands. The upper and lower limits of the 8 SCAs can be set independently in the software.

SCA8 serves a dual purpose – not only does it operate like the other SCAs, but it is also used to set the Region-of-Interest (ROI) for the Preset Count mode of MCA operation. That is, when a Preset Count is selected, the MCA will stop after the programmed number of counts occurs in the SCA8 ROI.





### Multichannel Scaler

The MultiChannel Scaler (MCS) produces spectral packets identical to those of the MCA, but they represent very different data. The MCS is used to measure total counts versus time rather than amplitude. Each "channel" in the spectrum represents a time interval. The MCS time base is commanded to a certain value, e.g. 0.5 sec. The system records all the counts in SCA8 during the first 0.5 second, writes this total into channel 1, records the counts in SCA8 during the second 0.5 second, writes this total into channel 2, and so on. The histogram memory can be used in either MCS or MCA mode (it cannot record in both modes simultaneously).

### 8.3.6 Electrical & Software Interfaces

There are three main elements to the electrical interface: communications, power, and auxiliary. The communications interfaces are the primary means to control the DP5 inside of the X-123SDD and to acquire the data. The DP5 supports USB, RS232, and Ethernet interfaces. With all three interfaces, commands are issued to set the many configuration parameters. The unit sends three classes of data packets back to the computer: status packets (which include the counter outputs), spectral data packets (which contain the MCA output array), and oscilloscope packets.

The DP5's software interface is very similar to that of the DP4 and PX4 and supports legacy software written for the older products, with minor modification. The DP5's configuration parameters are a superset of those found in the PX4, which is a superset of those found in the DP4. To provide backward compatibility with legacy software, the DP5 handles these three classes of parameters quite differently. The DP4 and PX4 use the same configuration data packets; the DP4 simply ignores the additional parameters which control options not available in the DP4 hardware. For backward compatibility, the DP5 recognizes the configuration packets of either the DP4 or the PX4, operating in a "DP4 emulation mode" or a "PX4 emulation mode". Since it needs all the parameters to operate properly, it reads the additional parameters from nonvolatile memory. These must be set via a new data packet, after which legacy software may be used, with minor modification.

Amptek's ADMCA software provides the quickest way to control and readout the DP5. It provides access to all of the configuration parameters in the DP5, lets one start and stop data acquisition, reads and displays the data, performs very simple analyses, and saves the data in an ASCII format. The files saved by ADMCA can be read by many spectral processing software packages.

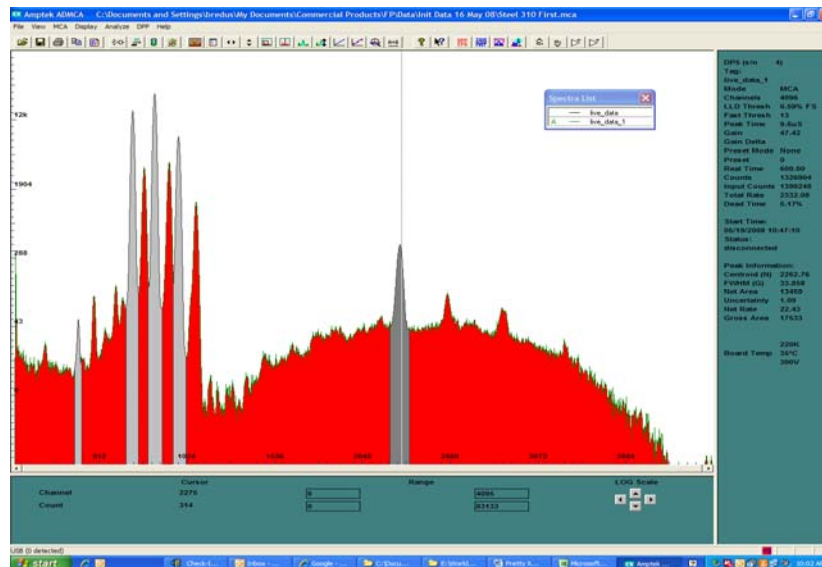
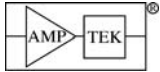


Figure 8-16. Typical screen display for ADMCA. This shows the characteristic X-rays emitted by a stainless steel alloy, excited by a 30 kVp X-ray tube and measured by an X-123SDD. The main window shows the spectral display. The user has defined regions of interest (ROIs) around the main peaks (shown in gray). The panel on the right displays counts, acquisition time, key parameters, and data regarding the selected ROI. The toolbar along top contains a button to access the configuration parameters, along with other frequently used functions.



Along with ADMCA, Amptek provides a DLL library of the routines used to interface to the DPP. A user can incorporate these into custom software. A demonstration program written in Visual Basic is provided. Amptek also provides an "Upload Manager", permitting new releases of the DP5s firmware and FPGA code to be programmed into the DP5 in the field, using the RS232 interface.

The auxiliary interface provides logic inputs and outputs which are not needed for the normal operation of the unit but which can be used for setup and debugging or for interfacing with external hardware. The DP5 includes two auxiliary outputs which can be commanded to show any of several signals. These are often displayed on an oscilloscope (along with the output of a DAC showing the signal processing in the FPGA) for setup and debugging. The SCA outputs are generally counted directly.

**8.4 UNDERSTANDING THE POWER SUPPLIES**

Figure 8-17 is a block diagram of the power supplies in the X-123SDD. There are quite a few voltages which must be produced. The DP5 itself requires several low voltages to operate the analog and digital circuitry. The detector and preamplifier require low voltages for the analog circuitry, plus a high voltage supply to bias the detector and supplies to operate the thermoelectric cooler. All of these are switching regulators for maximum efficiency. All of the DP5's supplies are located on the DP5 board itself, while the detector and preamplifier supplies are located on the PC5 board. The supplies on both boards are under the control of the DP5 microcontroller. The DP5 turns these supplies off and on and monitors the outputs via ADCs. In the HV and TEC supplies, the set point is under the control of the DP5.

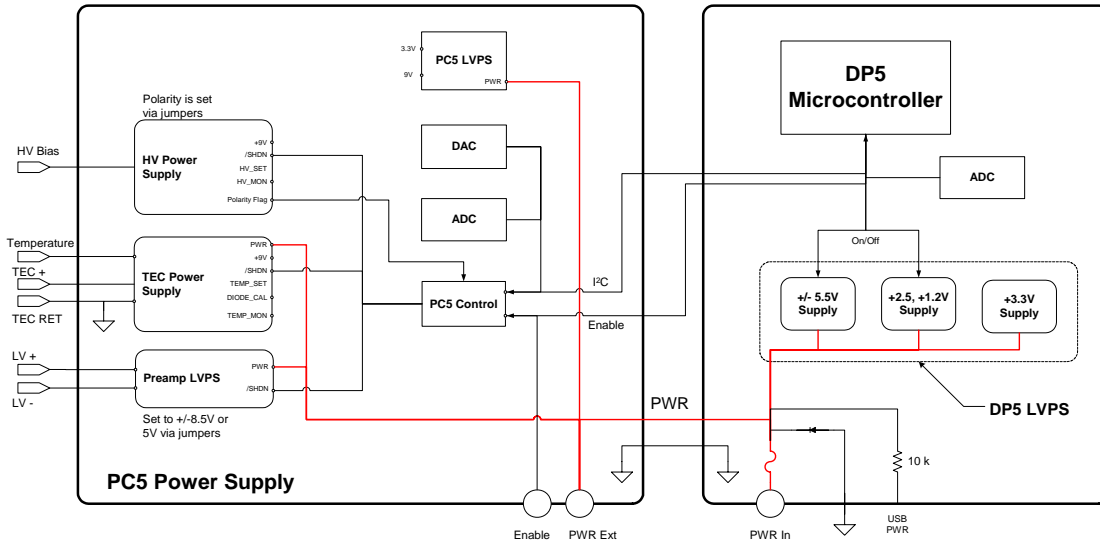
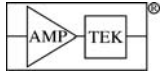


Figure 8-17. Block diagram of the power supplies in the X-123SDD.

Some key points of the overall architecture are as follows:

- The input power is nominally +5 VDC (4 V to 5.5 V acceptable). In the X-123SDD, the input connector is on the DP5. There is a fuse and reverse polarity protection, and then the input 5 VDC goes to the inputs of all of the separate supplies, on both boards.
- When the 5 VDC is plugged in, the 3.3V supply in the DP5 turns on and the digital circuitry is powered. When the DP5 is configured, it then turns on its internal low voltage supplies and the DP5 is powered. [The DP5 can be configured for this to happen automatically when power is applied.]
- In the PC5, the first step is checking the polarity of the HV bias supply. This is negative for SDD and positive for Amptek's other detectors. The DP5 compares the polarity set in the PC5 hardware to that selected in the DP5's "boot flags". If these do not match, then the PC5 supplies will not turn on.
- If the HV polarity in the PC5 hardware matches that of the software configuration, then the DP5 turns on the PC5 supplies. The set point for the HV bias is software selectable up to 1500V. The set point for the TEC supply is also software selectable. The temperature of the detector is measured by a diode in the detector package, and is used to provide closed loop temperature control with a maximum temperature differential of 85°C. The low voltage supplies for the preamp can be set to +/-5V or +/-8.5V, via a jumper on the board. In the X-123SDD it is preset at the factory to +/-5V.



- The power dissipated will depend on many variables. The most important is the  $\Delta T$  across the cooler. Reducing  $\Delta T$  by even a small amount from its maximum will decrease power dissipation significantly. The X-123SDD typically draws 2.5 W (500 mA at 5 V).
- Nominal switching frequencies are  $>1$  MHz, except for the HV bias, which switches at 50 kHz.

## 9 APPLICATION NOTES

### 9.1 Do's AND DON'TS

**DO READ THE WARNINGS AND CAUTIONS IN SECTION 3. THE X-123SDD INCLUDES MECHANICALLY DELICATE COMPONENTS AND HIGH VOLTAGES.** Failure to follow the instructions in Section 3 may cause personal injury or cause damage not covered by warranty.

- Keeping the heat sink cool is critical to obtaining the best performance!
  - The thermoelectric cooler keeps the detector up to 85°C cooler than the heat sink, the stud at the back of the AXR detector hybrid. To obtain the best performance, this stud must be kept as cool as feasible: if this stud heats excessively, the detector will heat and performance is worse.
  - Avoid holding the X-123SDD in the hand. Heat from the body will increase the operating temperature of the detector, degrading energy resolution. Keep it away from heat sources.
  - Mount the X-123SDD to a metal plate. This will increase the surface area and allow the detector to run 4 to 6 degrees colder. A colder detector will result in better energy resolution. As a rule, if the correct heat sinking has been provided, the X-123SDD should NOT be warm to the touch.
  - The gain and noise of the system depend on the temperature of the detector. For the best stability, find the maximum ambient temperature at which the system will operate, go to full cooling, and observe the temperature reached. Then set the temperature 5°C higher.
- Grounding is critical to the best performance.
  - Amptek **strongly** recommends using a single point ground for the system. Ground currents flowing through multiple connections, through a lab bench, etc. often induce noise.
  - We have observed several laptops in which the charger introduced ground noise. In these cases, better performance was found by (1) using a 3-prong to 2-prong adapter on the power supply of any notebook computer and (2) making a separate ground connection from the chassis of the X-123SDD. Note that the X-123SDD's AC/DC supply is isolated.
  - Place the X-123SDD away from computer terminals, CRT monitors, and magnetic fields. It is susceptible to radiated magnetic interference.
- Other setup suggestions
  - The system is somewhat susceptible to acoustic pickup, especially at higher frequencies. Minimize high frequency vibrations, either at the source or by mounting of the unit.
- Configuration suggestions
  - The "fast" and "slow" thresholds have a significant impact on performance. After setting other configuration options, reset the thresholds, either using the "Autotune" button or manually.
  - The baseline restoration setting can have a significant impact on performance. It stabilizes the spectrum over count rate but also suppresses low frequency noise and interference. Tuning BLR parameters can often improve or degrade resolution and spectral artifacts.